

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRI-i encoded:
				5 *
				6 * E658 VCVD - VECTOR CONVERT TO DECIMAL (32)
				7 * E65A VCVDG - VECTOR CONVERT TO DECIMAL (64)
				8 *
				9 * James Wekel June 2024
				10 *****
				11
				12 *****
				13 *
				14 * basic instruction tests
				15 *
				16 *****
				17 * This program tests proper functioning of the z/arch E6 VRI-i vector
				18 * convert to decimal. Exceptions are not tested.
				19 *
				20 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 * obvious coding errors. None of the tests are thorough. They are
				22 * NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 * *Testcase zvector-e6-13-converttodecimal: VECTOR E6 VRI-i instruction
				27 * *
				28 * * Zvector E6 tests for VRI-i encoded instruction:
				29 * *
				30 * * E658 VCVD - VECTOR CONVERT TO DECIMAL (32)
				31 * * E65A VCVDG - VECTOR CONVERT TO DECIMAL (64)
				32 * *
				33 * * # -----
				34 * * # This tests only the basic function of the instruction.
				35 * * # Exceptions are NOT tested.
				36 * * # -----
				37 * *
				38 * main size 2
				39 * numcpu 1
				40 * sysclear
				41 * archlvl z/Arch
				42 *
				43 * diag8cmd enable # (needed for messages to Hercules console)
				44 * loadcore "\$(testpath)/zvector-e6-13-converttodecimal.core" 0x0
				45 * diag8cmd disable # (reset back to default)
				46 *
				47 * *Done
				48 *
				49 *****
00000000		00000000	00003707	51 ZVE6TST START 0
				52 USING ZVE6TST, R0 Low core addressability
				53
		00000140	00000000	54 SV0LDPSW EQU ZVE6TST+X' 140' z/Arch Supervisor call old PSW

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						140 *****	
						141 * cc was not as expected	
						142 *****	
00000268	E310	0001	0082	00000268	00000001	143 CCMMSG EQU *	
0000026E	E310	5008	0076		00000001	144 XG R1, R1	
00000274	5410	82A8			00000008	145 LB R1, M4	m3 has CS bit
00000278	4780	804C			000004A8	146 N R1, =F' 1'	get CS (CC set) bit
					0000024C	147 BZ TESTREST	ignore if not set
						148 *	
						149 * extract CC extracted PSW	
						150 *	
0000027C	5810	8EE4			000010E4	151 L R1, CCPSW	
00000280	8810	000C			0000000C	152 SRL R1, 12	
00000284	5410	82AC			000004AC	153 N R1, =XL4' 3'	
00000288	4210	8EEC			000010EC	154 STC R1, CCFOUND	save cc
						155 *	
						156 * FILL IN MESSAGE	
						157 *	
0000028C	4820	5004			00000004	158 LH R2, TNUM	get test number and convert
00000290	4E20	8ED1			000010D1	159 CVD R2, DECNUM	
00000294	D211	8EBB	8EA5	000010BB	000010A5	160 MVC PRT3, EDIT	
0000029A	DE11	8EBB	8ED1	000010BB	000010D1	161 ED PRT3, DECNUM	
000002A0	D202	8E60	8EC8	00001060	000010C8	162 MVC CCPRTNUM(3), PRT3+13	fill in message with test #
						163	
000002A6	D207	8E7D	500B	0000107D	0000000B	164 MVC CCPRTNAME, OPNAME	fill in message with instruction
						165	
000002AC	B982	0022				166 XGR R2, R2	get CC as U8
000002B0	4320	5009			00000009	167 IC R2, CC	
000002B4	4E20	8ED1			000010D1	168 CVD R2, DECNUM	and convert
000002B8	D211	8EBB	8EA5	000010BB	000010A5	169 MVC PRT3, EDIT	
000002BE	DE11	8EBB	8ED1	000010BB	000010D1	170 ED PRT3, DECNUM	
000002C4	D200	8E93	8ECA	00001093	000010CA	171 MVC CCPRTEXP(1), PRT3+15	fill in message with CC field
						172	
000002CA	B982	0022				173 XGR R2, R2	get CCFOUND as U8
000002CE	4320	8EEC			000010EC	174 IC R2, CCFOUND	
000002D2	4E20	8ED1			000010D1	175 CVD R2, DECNUM	and convert
000002D6	D211	8EBB	8EA5	000010BB	000010A5	176 MVC PRT3, EDIT	
000002DC	DE11	8EBB	8ED1	000010BB	000010D1	177 ED PRT3, DECNUM	
000002E2	D200	8EA3	8ECA	000010A3	000010CA	178 MVC CCPRTGOT(1), PRT3+15	fill in message with ccfound
						179	
000002E8	4100	0055			00000055	180 LA R0, CCPRTLNG	message length
000002EC	4110	8E50			00001050	181 LA R1, CCPRTLNE	messagfe address
000002F0	45F0	817E			0000037E	182 BAL R15, RPTERROR	
						183	
000002F4	47F0	8160			00000360	184 B FAILCONT	

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						186	*****
						187	* result not as expected:
						188	* issue message with test number, instruction under test
						189	* and instruction l2
						190	*****
				000002F8	00000001	191	FAILMSG EQU *
000002F8	4820	5004			00000004	192	LH R2, TNUM get test number and convert
000002FC	4E20	8ED1			000010D1	193	CVD R2, DECNUM
00000300	D211	8EBB 8EA5		000010BB	000010A5	194	MVC PRT3, EDIT
00000306	DE11	8EBB 8ED1		000010BB	000010D1	195	ED PRT3, DECNUM
0000030C	D202	8E14 8EC8		00001014	000010C8	196	MVC PRTNUM(3), PRT3+13 fill in message with test #
						197	
00000312	D207	8E2F 500B		0000102F	0000000B	198	MVC PRTNAME, OPNAME fill in message with instruction
						199	
00000318	B982	0022				200	XGR R2, R2 get i3 as U8
0000031C	4320	5007			00000007	201	IC R2, I3 and convert
00000320	4E20	8ED1			000010D1	202	CVD R2, DECNUM
00000324	D211	8EBB 8EA5		000010BB	000010A5	203	MVC PRT3, EDIT
0000032A	DE11	8EBB 8ED1		000010BB	000010D1	204	ED PRT3, DECNUM
00000330	D202	8E40 8EC8		00001040	000010C8	205	MVC PRTI3(3), PRT3+13 fill in message with i3 field
						206	
00000336	B982	0022				207	XGR R2, R2 get m4 as U8
0000033A	4320	5008			00000008	208	IC R2, M4 and convert
0000033E	4E20	8ED1			000010D1	209	CVD R2, DECNUM
00000342	D211	8EBB 8EA5		000010BB	000010A5	210	MVC PRT3, EDIT
00000348	DE11	8EBB 8ED1		000010BB	000010D1	211	ED PRT3, DECNUM
0000034E	D202	8E4D 8EC9		0000104D	000010C9	212	MVC PRTM4(3), PRT3+14 fill in message with m4 field
						213	
00000354	4100	004C			0000004C	214	LA R0, PRTLNG message length
00000358	4110	8E04			00001004	215	LA R1, PRTLNE messagfe address
0000035C	45F0	817E			0000037E	216	BAL R15, RPTERROR
						218	*****
						219	* continue after a failed test
						220	*****
				00000360	00000001	221	FAILCONT EQU *
00000360	5800	82A8			000004A8	222	L R0, =F' 1' set GLOBAL failed test indicator
00000364	5000	8E00			00001000	223	ST R0, FAILED
						224	
00000368	41C0	C004			00000004	225	LA R12, 4(0, R12) next test address
0000036C	47F0	802A			0000022A	226	B NEXTE6
						228	*****
						229	* end of testing; set ending psw
						230	*****
				00000370	00000001	231	ENDTEST EQU *
00000370	5810	8E00			00001000	232	L R1, FAILED did a test fail?
00000374	1211					233	LTR R1, R1
00000376	4780	8280			00000480	234	BZ EOJ No, exit
0000037A	47F0	8298			00000498	235	B FAILTEST Yes, exit with BAD PSW
						236	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				297	*****
				298	* Normal completion or Abnormal termination PSWs
				299	*****
00000470	00020001 80000000			301	E0JPSW DC 0D' 0' , X' 0002000180000000' , AD(0)
00000480	B2B2 8270		00000470	303	E0J LPSWE E0JPSW Normal completion
00000488	00020001 80000000			305	FAILPSW DC 0D' 0' , X' 0002000180000000' , AD(X' BAD')
00000498	B2B2 8288		00000488	307	FAILTEST LPSWE FAILPSW Abnormal termination
				309	*****
				310	* Working Storage
				311	*****
0000049C	00000000			313	CTLRO DS F CRO
000004A0	00000000			314	DS F
				315	
000004A4	00003558			316	E6TADR DC A(E6TESTS) address of E6 test table
000004A8				318	LTORG , Literals pool
000004A8	00000001			319	=F' 1'
000004AC	00000003			320	=XL4' 3'
000004B0	0000			321	=H' 0'
000004B2	005F			322	=AL2(L' MSGMSG)
				323	
				324	* some constants
				325	
	00000400	00000001		326	K EQU 1024 One KB
	00001000	00000001		327	PAGE EQU (4*K) Size of one page
	00010000	00000001		328	K64 EQU (64*K) 64 KB
	00100000	00000001		329	MB EQU (K*K) 1 MB
				330	
				331	
	AABBCCDD	00000001		332	REG2PATT EQU X' AABBCCDD' Polluted Register pattern
	000000DD	00000001		333	REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				436 *****	
				437 * Macros to help build test tables	
				438 *-----	
				439 * VRR_K Macro to help build test tables	
				440 *****	
				441 MACRO	
				442 VRR_K &INST, &I3, &M4, &CC	
				443 . *	&INST - instruction under test
				444 . *	&I3
				445 . *	&M4
				446 . *	&CC - expected CC
				447 . *	
				448 LCLA &XCC(4) &CC has mask values for FAILED condition codes	
				449 &XCC(1) SETA 7	CC != 0
				450 &XCC(2) SETA 11	CC != 1
				451 &XCC(3) SETA 13	CC != 2
				452 &XCC(4) SETA 14	CC != 3
				453	
				454 GBLA &TNUM	
				455 &TNUM SETA &TNUM+1	
				456	
				457 DS 0FD	
				458 USING *, R5	base for test data and test routine
				459	
				460 T&TNUM DC A(X&TNUM)	address of test routine
				461 DC H' &TNUM	test number
				462 DC XL1' 00'	
				463 DC HL1' &I3'	i3
				464 DC HL1' &M4'	m4
				465 DC HL1' &CC'	cc
				466 DC HL1' &XCC(&CC+1)'	cc failed mask
				467	
				468 DC CL8' &INST'	instruction name
				469	
				470 DC A(16)	result length
				471 REA&TNUM DC A(RE&TNUM)	result address
				472 . *	
				473 *	INSTRUCTION UNDER TEST ROUTINE
				474 X&TNUM DS 0F	
				475 VL V1, V1FUDGE	pollute V1
				476 LG R2, RE&TNUM+16	get R2 source
				477	
				478 &INST V1, R2, &I3, &M4	test instruction
				479	
				480 VST V1, V10OUTPUT	save
				481 EPSW R2, R0	exptract psw
				482 ST R2, CCPSW	to save CC
				483	
				484 BR R11	return
				485	
				486 RE&TNUM DC 0F	
				487 DROP R5	
				488	
				489 MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001288	00000000 0000001D					
00001290	FFFFFFFF FFFFFFFF			623	DC FD' - 1'	R2 source
				624		
				625	VRR_K VCVD, 159, 1, 0	INT_MAX
00001298				626+	DS OFD	
00001298		00001298		627+	USING *, R5	base for test data and test routine
00001298	000012B4			628+T4	DC A(X4)	address of test routine
0000129C	0004			629+	DC H' 4'	test number
0000129E	00			630+	DC XL1' 00'	
0000129F	9F			631+	DC HL1' 159'	i3
000012A0	01			632+	DC HL1' 1'	m4
000012A1	00			633+	DC HL1' 0'	cc
000012A2	07			634+	DC HL1' 7'	cc failed mask
000012A3	E5C3E5C4 40404040			635+	DC CL8' VCVD'	instruction name
000012AC	00000010			636+	DC A(16)	result length
000012B0	000012D8			637+REA4	DC A(RE4)	result address
				638+*		INSTRUCTION UNDER TEST ROUTINE
000012B4				639+X4	DS OF	
000012B4	E710 8F40 0006		00001140	640+	VL V1, V1FUDGE	pollute V1
000012BA	E320 5050 0004		000012E8	641+	LG R2, RE4+16	get R2 source
000012C0	E612 0019 F058			642+	VCVD V1, R2, 159, 1	test instruction
000012C6	E710 8F08 000E		00001108	643+	VST V1, V10UTPUT	save
000012CC	B98D 0020			644+	EPSW R2, R0	exptract psw
000012D0	5020 8EE4		000010E4	645+	ST R2, CCPSW	to save CC
000012D4	07FB			646+	BR R11	return
000012D8				647+RE4	DC OF	
000012D8				648+	DROP R5	
000012D8	00000000 00000000			649	DC XL16' 00000000000000000000000002147483647C'	V1 result
000012E0	00000214 7483647C					
000012E8	00000000 7FFFFFFF			650	DC FD' 2147483647'	R2 source
				651		
				652	VRR_K VCVD, 159, 1, 0	INT_MIN
000012F0				653+	DS OFD	
000012F0		000012F0		654+	USING *, R5	base for test data and test routine
000012F0	0000130C			655+T5	DC A(X5)	address of test routine
000012F4	0005			656+	DC H' 5'	test number
000012F6	00			657+	DC XL1' 00'	
000012F7	9F			658+	DC HL1' 159'	i3
000012F8	01			659+	DC HL1' 1'	m4
000012F9	00			660+	DC HL1' 0'	cc
000012FA	07			661+	DC HL1' 7'	cc failed mask
000012FB	E5C3E5C4 40404040			662+	DC CL8' VCVD'	instruction name
00001304	00000010			663+	DC A(16)	result length
00001308	00001330			664+REA5	DC A(RE5)	result address
				665+*		INSTRUCTION UNDER TEST ROUTINE
0000130C				666+X5	DS OF	
0000130C	E710 8F40 0006		00001140	667+	VL V1, V1FUDGE	pollute V1
00001312	E320 5050 0004		00001340	668+	LG R2, RE5+16	get R2 source
00001318	E612 0019 F058			669+	VCVD V1, R2, 159, 1	test instruction
0000131E	E710 8F08 000E		00001108	670+	VST V1, V10UTPUT	save
00001324	B98D 0020			671+	EPSW R2, R0	exptract psw
00001328	5020 8EE4		000010E4	672+	ST R2, CCPSW	to save CC
0000132C	07FB			673+	BR R11	return
00001330				674+RE5	DC OF	
00001330				675+	DROP R5	
00001330	00000000 00000000			676	DC XL16' 00000000000000000000000002147483648D'	V1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001338	00000214 7483648D					
00001340	FFFFFFFF 80000000			677	DC	FD' - 2147483648' R2 source
				678		
				679 *	VCVD	m4= 1 (LB=0, P1=0 , CS=1)
				680 *		i3= 137 (IOM=1, RDC= 9)
				681		
				682	VRR_K	VCVD, 137, 1, 0
00001348				683+	DS	OFD
00001348		00001348		684+	USING	*, R5 base for test data and test routine
00001348	00001364			685+T6	DC	A(X6) address of test routine
0000134C	0006			686+	DC	H' 6' test number
0000134E	00			687+	DC	XL1' 00'
0000134F	89			688+	DC	HL1' 137' i3
00001350	01			689+	DC	HL1' 1' m4
00001351	00			690+	DC	HL1' 0' cc
00001352	07			691+	DC	HL1' 7' cc failed mask
00001353	E5C3E5C4 40404040			692+	DC	CL8' VCVD' instruction name
0000135C	00000010			693+	DC	A(16) result length
00001360	00001388			694+REA6	DC	A(RE6) result address
				695+*		INSTRUCTION UNDER TEST ROUTINE
00001364				696+X6	DS	OF
00001364	E710 8F40 0006		00001140	697+	VL	V1, V1FUDGE pollute V1
0000136A	E320 5050 0004		00001398	698+	LG	R2, RE6+16 get R2 source
00001370	E612 0018 9058			699+	VCVD	V1, R2, 137, 1 test instruction
00001376	E710 8F08 000E		00001108	700+	VST	V1, V10UTPUT save
0000137C	B98D 0020			701+	EPSW	R2, R0 exptract psw
00001380	5020 8EE4		000010E4	702+	ST	R2, CCPSW to save CC
00001384	07FB			703+	BR	R11 return
00001388				704+RE6	DC	OF
00001388				705+	DROP	R5
00001388	00000000 00000000			706	DC	XL16' 00000000000000000000000000000000C' V1 result
00001390	00000000 0000000C					
00001398	00000000 00000000			707	DC	FD' 0' R2 source
				708		
				709	VRR_K	VCVD, 137, 1, 0
000013A0				710+	DS	OFD
000013A0		000013A0		711+	USING	*, R5 base for test data and test routine
000013A0	000013BC			712+T7	DC	A(X7) address of test routine
000013A4	0007			713+	DC	H' 7' test number
000013A6	00			714+	DC	XL1' 00'
000013A7	89			715+	DC	HL1' 137' i3
000013A8	01			716+	DC	HL1' 1' m4
000013A9	00			717+	DC	HL1' 0' cc
000013AA	07			718+	DC	HL1' 7' cc failed mask
000013AB	E5C3E5C4 40404040			719+	DC	CL8' VCVD' instruction name
000013B4	00000010			720+	DC	A(16) result length
000013B8	000013E0			721+REA7	DC	A(RE7) result address
				722+*		INSTRUCTION UNDER TEST ROUTINE
000013BC				723+X7	DS	OF
000013BC	E710 8F40 0006		00001140	724+	VL	V1, V1FUDGE pollute V1
000013C2	E320 5050 0004		000013F0	725+	LG	R2, RE7+16 get R2 source
000013C8	E612 0018 9058			726+	VCVD	V1, R2, 137, 1 test instruction
000013CE	E710 8F08 000E		00001108	727+	VST	V1, V10UTPUT save
000013D4	B98D 0020			728+	EPSW	R2, R0 exptract psw
000013D8	5020 8EE4		000010E4	729+	ST	R2, CCPSW to save CC
000013DC	07FB			730+	BR	R11 return

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT		
00001490					785+RE9	DC	OF
00001490					786+	DROP	R5
00001490	00000000	00000000			787	DC	XL16' 000000000000000000000000147483647C'
00001498	00000014	7483647C					V1 result
000014A0	00000000	7FFFFFFF			788	DC	FD' 2147483647'
					789		R2 source
					790	VRR_K	VCVD, 137, 1, 3
000014A8					791+	DS	INT_MIN
000014A8			000014A8		792+	USING	*, R5
000014A8	000014C4				793+T10	DC	base for test data and test routine
000014AC	000A				794+	DC	address of test routine
000014AE	00				795+	DC	test number
000014AF	89				796+	DC	XL1' 00'
000014B0	01				797+	DC	HL1' 137'
000014B1	03				798+	DC	i3
000014B2	0E				799+	DC	m4
000014B3	E5C3E5C4	40404040			800+	DC	cc
000014BC	00000010				801+	DC	cc failed mask
000014C0	000014E8				802+REA10	DC	instruction name
					803+*		result length
000014C4					804+X10	DS	result address
000014C4	E710 8F40 0006			00001140	805+	VL	INSTRUCTION UNDER TEST ROUTINE
000014CA	E320 5050 0004			000014F8	806+	LG	
000014D0	E612 0018 9058				807+	VCVD	pollute V1
000014D6	E710 8F08 000E			00001108	808+	VST	get R2 source
000014DC	B98D 0020				809+	EPSW	test instruction
000014E0	5020 8EE4			000010E4	810+	ST	save
000014E4	07FB				811+	BR	exptrect psw
000014E8					812+RE10	DC	to save CC
000014E8					813+	DROP	return
000014E8	00000000	00000000			814	DC	
000014F0	00000014	7483648D					V1 result
000014F8	FFFFFFFF	80000000			815	DC	XL16' 000000000000000000000000147483648D'
					816		
					817 *		
					818 * VCVD		m4= 3 (LB=0, P1=1 , CS=1)
					819 *		i3= 159 (IOM=1, RDC=31)
					820		
					821	VRR_K	VCVD, 159, 3, 0
00001500					822+	DS	
00001500			00001500		823+	USING	*, R5
00001500	0000151C				824+T11	DC	base for test data and test routine
00001504	000B				825+	DC	address of test routine
00001506	00				826+	DC	test number
00001507	9F				827+	DC	XL1' 00'
00001508	03				828+	DC	HL1' 159'
00001509	00				829+	DC	HL1' 3'
0000150A	07				830+	DC	HL1' 0'
0000150B	E5C3E5C4	40404040			831+	DC	HL1' 7'
00001514	00000010				832+	DC	cc failed mask
00001518	00001540				833+REA11	DC	instruction name
					834+*		result length
0000151C					835+X11	DS	result address
0000151C	E710 8F40 0006			00001140	836+	VL	INSTRUCTION UNDER TEST ROUTINE
00001522	E320 5050 0004			00001550	837+	LG	
00001528	E612 0039 F058				838+	VCVD	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000152E	E710 8F08 000E		00001108	839+	VST	V1, V10OUTPUT	save
00001534	B98D 0020			840+	EPSW	R2, R0	exptrect psw
00001538	5020 8EE4		000010E4	841+	ST	R2, CCPSW	to save CC
0000153C	07FB			842+	BR	R11	return
00001540				843+RE11	DC	0F	
00001540				844+	DROP	R5	
00001540	00000000 00000000			845	DC	XL16' 00000000000000000000000000000000F'	V1 result
00001548	00000000 0000000F						
00001550	00000000 00000000			846	DC	FD' 0'	R2 source
				847			
				848	VRR_K	VCVD, 159, 3, 0	
00001558				849+	DS	0FD	
00001558		00001558		850+	USING	*, R5	base for test data and test routine
00001558	00001574			851+T12	DC	A(X12)	address of test routine
0000155C	000C			852+	DC	H' 12'	test number
0000155E	00			853+	DC	XL1' 00'	
0000155F	9F			854+	DC	HL1' 159'	i3
00001560	03			855+	DC	HL1' 3'	m4
00001561	00			856+	DC	HL1' 0'	cc
00001562	07			857+	DC	HL1' 7'	cc failed mask
00001563	E5C3E5C4 40404040			858+	DC	CL8' VCVD'	instruction name
0000156C	00000010			859+	DC	A(16)	result length
00001570	00001598			860+REA12	DC	A(RE12)	result address
				861+*			INSTRUCTION UNDER TEST ROUTINE
00001574				862+X12	DS	0F	
00001574	E710 8F40 0006		00001140	863+	VL	V1, V1FUDGE	pollute V1
0000157A	E320 5050 0004		000015A8	864+	lg	R2, RE12+16	get R2 source
00001580	E612 0039 F058			865+	VCVD	V1, R2, 159, 3	test instruction
00001586	E710 8F08 000E		00001108	866+	VST	V1, V10OUTPUT	save
0000158C	B98D 0020			867+	EPSW	R2, R0	exptrect psw
00001590	5020 8EE4		000010E4	868+	ST	R2, CCPSW	to save CC
00001594	07FB			869+	BR	R11	return
00001598				870+RE12	DC	0F	
00001598				871+	DROP	R5	
00001598	00000000 00000000			872	DC	XL16' 000000000000000000000000000000001F'	V1 result
000015A0	00000000 0000001F						
000015A8	00000000 00000001			873	DC	FD' 1'	R2 source
				874			
				875	VRR_K	VCVD, 159, 3, 0	
000015B0				876+	DS	0FD	
000015B0		000015B0		877+	USING	*, R5	base for test data and test routine
000015B0	000015CC			878+T13	DC	A(X13)	address of test routine
000015B4	000D			879+	DC	H' 13'	test number
000015B6	00			880+	DC	XL1' 00'	
000015B7	9F			881+	DC	HL1' 159'	i3
000015B8	03			882+	DC	HL1' 3'	m4
000015B9	00			883+	DC	HL1' 0'	cc
000015BA	07			884+	DC	HL1' 7'	cc failed mask
000015BB	E5C3E5C4 40404040			885+	DC	CL8' VCVD'	instruction name
000015C4	00000010			886+	DC	A(16)	result length
000015C8	000015F0			887+REA13	DC	A(RE13)	result address
				888+*			INSTRUCTION UNDER TEST ROUTINE
000015CC				889+X13	DS	0F	
000015CC	E710 8F40 0006		00001140	890+	VL	V1, V1FUDGE	pollute V1
000015D2	E320 5050 0004		00001600	891+	lg	R2, RE13+16	get R2 source
000015D8	E612 0039 F058			892+	VCVD	V1, R2, 159, 3	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
0000168E	E710 8F08 000E		00001108	947+	VST	V1, V10OUTPUT	save	
00001694	B98D 0020			948+	EPSW	R2, R0	exptract psw	
00001698	5020 8EE4		000010E4	949+	ST	R2, CCPSW	to save CC	
0000169C	07FB			950+	BR	R11	return	
000016A0				951+RE15	DC	0F		
000016A0				952+	DROP	R5		
000016A0	00000000 00000000			953	DC	XL16' 0000000000000000000000002147483648F'	V1 result	
000016A8	00000214 7483648F							
000016B0	FFFFFFFF 80000000			954	DC	FD' - 2147483648'	R2 source	
				955				
				956 * VCVD		m4= 3 (LB=0, P1=1 , CS=1)		
				957 *		i3= 137 (IOM=1, RDC= 9)		
				958				
				959	VRR_K	VCVD, 137, 3, 0		
000016B8				960+	DS	0FD		
000016B8		000016B8		961+	USING	*, R5	base for test data and test routine	
000016B8	000016D4			962+T16	DC	A(X16)	address of test routine	
000016BC	0010			963+	DC	H' 16'	test number	
000016BE	00			964+	DC	XL1' 00'		
000016BF	89			965+	DC	HL1' 137'	i3	
000016C0	03			966+	DC	HL1' 3'	m4	
000016C1	00			967+	DC	HL1' 0'	cc	
000016C2	07			968+	DC	HL1' 7'	cc failed mask	
000016C3	E5C3E5C4 40404040			969+	DC	CL8' VCVD'	instruction name	
000016CC	00000010			970+	DC	A(16)	result length	
000016D0	000016F8			971+REA16	DC	A(RE16)	result address	
				972+*			INSTRUCTION UNDER TEST ROUTINE	
000016D4				973+X16	DS	0F		
000016D4	E710 8F40 0006		00001140	974+	VL	V1, V1FUDGE	pollute V1	
000016DA	E320 5050 0004		00001708	975+	LG	R2, RE16+16	get R2 source	
000016E0	E612 0038 9058			976+	VCVD	V1, R2, 137, 3	test instruction	
000016E6	E710 8F08 000E		00001108	977+	VST	V1, V10OUTPUT	save	
000016EC	B98D 0020			978+	EPSW	R2, R0	exptract psw	
000016F0	5020 8EE4		000010E4	979+	ST	R2, CCPSW	to save CC	
000016F4	07FB			980+	BR	R11	return	
000016F8				981+RE16	DC	0F		
000016F8				982+	DROP	R5		
000016F8	00000000 00000000			983	DC	XL16' 00000000000000000000000000000000F'	V1 result	
00001700	00000000 0000000F							
00001708	00000000 00000000			984	DC	FD' 0'	R2 source	
				985				
				986	VRR_K	VCVD, 137, 3, 0		
00001710				987+	DS	0FD		
00001710		00001710		988+	USING	*, R5	base for test data and test routine	
00001710	0000172C			989+T17	DC	A(X17)	address of test routine	
00001714	0011			990+	DC	H' 17'	test number	
00001716	00			991+	DC	XL1' 00'		
00001717	89			992+	DC	HL1' 137'	i3	
00001718	03			993+	DC	HL1' 3'	m4	
00001719	00			994+	DC	HL1' 0'	cc	
0000171A	07			995+	DC	HL1' 7'	cc failed mask	
0000171B	E5C3E5C4 40404040			996+	DC	CL8' VCVD'	instruction name	
00001724	00000010			997+	DC	A(16)	result length	
00001728	00001750			998+REA17	DC	A(RE17)	result address	
				999+*			INSTRUCTION UNDER TEST ROUTINE	
0000172C				1000+X17	DS	0F		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001884	00000010			1109+	DC	A(16)	result length
00001888	000018B0			1110+REA21	DC	A(RE21)	result address
				1111+*			INSTRUCTION UNDER TEST ROUTINE
0000188C				1112+X21	DS	0F	
0000188C	E710 8F40 0006		00001140	1113+	VL	V1, V1FUDGE	pollute V1
00001892	E320 5050 0004		000018C0	1114+	LG	R2, RE21+16	get R2 source
00001898	E612 0099 F058			1115+	VCVD	V1, R2, 159, 9	test instruction
0000189E	E710 8F08 000E		00001108	1116+	VST	V1, V10UTPUT	save
000018A4	B98D 0020			1117+	EPSW	R2, R0	exptract psw
000018A8	5020 8EE4		000010E4	1118+	ST	R2, CCPSW	to save CC
000018AC	07FB			1119+	BR	R11	return
000018B0				1120+RE21	DC	0F	
000018B0				1121+	DROP	R5	
000018B0	00000000 00000000			1122	DC	XL16' 00000000000000000000000000000000C'	V1 result
000018B8	00000000 0000000C						
000018C0	00000000 00000000			1123	DC	FD' 0'	R2 source
				1124			
				1125	VRR_K	VCVD, 159, 9, 0	
000018C8				1126+	DS	0FD	
000018C8		000018C8		1127+	USING	*, R5	base for test data and test routine
000018C8	000018E4			1128+T22	DC	A(X22)	address of test routine
000018CC	0016			1129+	DC	H' 22'	test number
000018CE	00			1130+	DC	XL1' 00'	
000018CF	9F			1131+	DC	HL1' 159'	i3
000018D0	09			1132+	DC	HL1' 9'	m4
000018D1	00			1133+	DC	HL1' 0'	cc
000018D2	07			1134+	DC	HL1' 7'	cc failed mask
000018D3	E5C3E5C4 40404040			1135+	DC	CL8' VCVD'	instruction name
000018DC	00000010			1136+	DC	A(16)	result length
000018E0	00001908			1137+REA22	DC	A(RE22)	result address
				1138+*			INSTRUCTION UNDER TEST ROUTINE
000018E4				1139+X22	DS	0F	
000018E4	E710 8F40 0006		00001140	1140+	VL	V1, V1FUDGE	pollute V1
000018EA	E320 5050 0004		00001918	1141+	LG	R2, RE22+16	get R2 source
000018F0	E612 0099 F058			1142+	VCVD	V1, R2, 159, 9	test instruction
000018F6	E710 8F08 000E		00001108	1143+	VST	V1, V10UTPUT	save
000018FC	B98D 0020			1144+	EPSW	R2, R0	exptract psw
00001900	5020 8EE4		000010E4	1145+	ST	R2, CCPSW	to save CC
00001904	07FB			1146+	BR	R11	return
00001908				1147+RE22	DC	0F	
00001908				1148+	DROP	R5	
00001908	00000000 00000000			1149	DC	XL16' 000000000000000000000000000000001C'	V1 result
00001910	00000000 0000001C						
00001918	00000000 00000001			1150	DC	FD' 1'	R2 source
				1151			
				1152	VRR_K	VCVD, 159, 9, 0	UINT_MAX
00001920				1153+	DS	0FD	
00001920		00001920		1154+	USING	*, R5	base for test data and test routine
00001920	0000193C			1155+T23	DC	A(X23)	address of test routine
00001924	0017			1156+	DC	H' 23'	test number
00001926	00			1157+	DC	XL1' 00'	
00001927	9F			1158+	DC	HL1' 159'	i3
00001928	09			1159+	DC	HL1' 9'	m4
00001929	00			1160+	DC	HL1' 0'	cc
0000192A	07			1161+	DC	HL1' 7'	cc failed mask
0000192B	E5C3E5C4 40404040			1162+	DC	CL8' VCVD'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001934	00000010			1163+	DC	A(16)	result length
00001938	00001960			1164+REA23	DC	A(RE23)	result address
				1165+*			INSTRUCTION UNDER TEST ROUTINE
0000193C				1166+X23	DS	0F	
0000193C	E710 8F40 0006		00001140	1167+	VL	V1, V1FUDGE	pollute V1
00001942	E320 5050 0004		00001970	1168+	LG	R2, RE23+16	get R2 source
00001948	E612 0099 F058			1169+	VCVD	V1, R2, 159, 9	test instruction
0000194E	E710 8F08 000E		00001108	1170+	VST	V1, V10UTPUT	save
00001954	B98D 0020			1171+	EPSW	R2, R0	exptract psw
00001958	5020 8EE4		000010E4	1172+	ST	R2, CCPSW	to save CC
0000195C	07FB			1173+	BR	R11	return
00001960				1174+RE23	DC	0F	
00001960				1175+	DROP	R5	
00001960	00000000 00000000			1176	DC	XL16' 0000000000000000000000004294967295C'	V1 result
00001968	00000429 4967295C						
00001970	FFFFFFFF FFFFFFFF			1177	DC	FD' - 1'	R2 source
				1178			
				1179	VRR_K	VCVD, 159, 9, 0	INT_MAX
00001978				1180+	DS	0FD	
00001978		00001978		1181+	USING	*, R5	base for test data and test routine
00001978	00001994			1182+T24	DC	A(X24)	address of test routine
0000197C	0018			1183+	DC	H' 24'	test number
0000197E	00			1184+	DC	XL1' 00'	
0000197F	9F			1185+	DC	HL1' 159'	i3
00001980	09			1186+	DC	HL1' 9'	m4
00001981	00			1187+	DC	HL1' 0'	cc
00001982	07			1188+	DC	HL1' 7'	cc failed mask
00001983	E5C3E5C4 40404040			1189+	DC	CL8' VCVD'	instruction name
0000198C	00000010			1190+	DC	A(16)	result length
00001990	000019B8			1191+REA24	DC	A(RE24)	result address
				1192+*			INSTRUCTION UNDER TEST ROUTINE
00001994				1193+X24	DS	0F	
00001994	E710 8F40 0006		00001140	1194+	VL	V1, V1FUDGE	pollute V1
0000199A	E320 5050 0004		000019C8	1195+	LG	R2, RE24+16	get R2 source
000019A0	E612 0099 F058			1196+	VCVD	V1, R2, 159, 9	test instruction
000019A6	E710 8F08 000E		00001108	1197+	VST	V1, V10UTPUT	save
000019AC	B98D 0020			1198+	EPSW	R2, R0	exptract psw
000019B0	5020 8EE4		000010E4	1199+	ST	R2, CCPSW	to save CC
000019B4	07FB			1200+	BR	R11	return
000019B8				1201+RE24	DC	0F	
000019B8				1202+	DROP	R5	
000019B8	00000000 00000000			1203	DC	XL16' 0000000000000000000000002147483647C'	V1 result
000019C0	00000214 7483647C						
000019C8	00000000 7FFFFFFF			1204	DC	FD' 2147483647'	R2 source
				1205			
				1206	VRR_K	VCVD, 159, 9, 0	INT_MIN
000019D0				1207+	DS	0FD	
000019D0		000019D0		1208+	USING	*, R5	base for test data and test routine
000019D0	000019EC			1209+T25	DC	A(X25)	address of test routine
000019D4	0019			1210+	DC	H' 25'	test number
000019D6	00			1211+	DC	XL1' 00'	
000019D7	9F			1212+	DC	HL1' 159'	i3
000019D8	09			1213+	DC	HL1' 9'	m4
000019D9	00			1214+	DC	HL1' 0'	cc
000019DA	07			1215+	DC	HL1' 7'	cc failed mask
000019DB	E5C3E5C4 40404040			1216+	DC	CL8' VCVD'	instruction name

LOC	OBJECT CODE			ADDR1	ADDR2	STMT			
000019E4	00000010					1217+	DC	A(16)	result length
000019E8	00001A10					1218+REA25	DC	A(RE25)	result address
						1219+*	INSTRUCTION UNDER TEST ROUTINE		
000019EC						1220+X25	DS	OF	
000019EC	E710	8F40	0006		00001140	1221+	VL	V1, V1FUDGE	pollute V1
000019F2	E320	5050	0004		00001A20	1222+	LG	R2, RE25+16	get R2 source
000019F8	E612	0099	F058			1223+	VCVD	V1, R2, 159, 9	test instruction
000019FE	E710	8F08	000E		00001108	1224+	VST	V1, V10UTPUT	save
00001A04	B98D	0020				1225+	EPSW	R2, R0	exptract psw
00001A08	5020	8EE4			000010E4	1226+	ST	R2, CCPSW	to save CC
00001A0C	07FB					1227+	BR	R11	return
00001A10						1228+RE25	DC	OF	
00001A10						1229+	DROP	R5	
00001A10	00000000	00000000				1230	DC	XL16' 0000000000000000000000002147483648C'	V1 result t
00001A18	00000214	7483648C							
00001A20	FFFFFFFF	80000000				1231	DC	FD' - 2147483648'	R2 source
						1232			
						1233 * VCVD		m4= 9 (LB=1, P1=0 , CS=1)	
						1234 *		i3= 137 (IOM=1, RDC= 9)	
						1235			
						1236	VRR_K	VCVD, 137, 9, 0	
00001A28						1237+	DS	OFD	
00001A28				00001A28		1238+	USING	*, R5	base for test data and test routine
00001A28	00001A44					1239+T26	DC	A(X26)	address of test routine
00001A2C	001A					1240+	DC	H' 26'	test number
00001A2E	00					1241+	DC	XL1' 00'	
00001A2F	89					1242+	DC	HL1' 137'	i3
00001A30	09					1243+	DC	HL1' 9'	m4
00001A31	00					1244+	DC	HL1' 0'	cc
00001A32	07					1245+	DC	HL1' 7'	cc failed mask
00001A33	E5C3E5C4	40404040				1246+	DC	CL8' VCVD'	instruction name
00001A3C	00000010					1247+	DC	A(16)	result length
00001A40	00001A68					1248+REA26	DC	A(RE26)	result address
						1249+*	INSTRUCTION UNDER TEST ROUTINE		
00001A44						1250+X26	DS	OF	
00001A44	E710	8F40	0006		00001140	1251+	VL	V1, V1FUDGE	pollute V1
00001A4A	E320	5050	0004		00001A78	1252+	LG	R2, RE26+16	get R2 source
00001A50	E612	0098	9058			1253+	VCVD	V1, R2, 137, 9	test instruction
00001A56	E710	8F08	000E		00001108	1254+	VST	V1, V10UTPUT	save
00001A5C	B98D	0020				1255+	EPSW	R2, R0	exptract psw
00001A60	5020	8EE4			000010E4	1256+	ST	R2, CCPSW	to save CC
00001A64	07FB					1257+	BR	R11	return
00001A68						1258+RE26	DC	OF	
00001A68						1259+	DROP	R5	
00001A68	00000000	00000000				1260	DC	XL16' 00000000000000000000000000000000C'	V1 result t
00001A70	00000000	0000000C							
00001A78	00000000	00000000				1261	DC	FD' 0'	R2 source
						1262			
						1263	VRR_K	VCVD, 137, 9, 0	
00001A80						1264+	DS	OFD	
00001A80				00001A80		1265+	USING	*, R5	base for test data and test routine
00001A80	00001A9C					1266+T27	DC	A(X27)	address of test routine
00001A84	001B					1267+	DC	H' 27'	test number
00001A86	00					1268+	DC	XL1' 00'	
00001A87	89					1269+	DC	HL1' 137'	i3
00001A88	09					1270+	DC	HL1' 9'	m4

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001BE4	001F			1379+	DC	H' 31' test number
00001BE6	00			1380+	DC	XL1' 00'
00001BE7	9F			1381+	DC	HL1' 159' i3
00001BE8	0B			1382+	DC	HL1' 11' m4
00001BE9	00			1383+	DC	HL1' 0' cc
00001BEA	07			1384+	DC	HL1' 7' cc failed mask
00001BEB	E5C3E5C4 40404040			1385+	DC	CL8' VCVD' instruction name
00001BF4	00000010			1386+	DC	A(16) result length
00001BF8	00001C20			1387+REA31	DC	A(RE31) result address
				1388+*		INSTRUCTION UNDER TEST ROUTINE
00001BFC				1389+X31	DS	0F
00001BFC	E710 8F40 0006		00001140	1390+	VL	V1, V1FUDGE pollute V1
00001C02	E320 5050 0004		00001C30	1391+	LG	R2, RE31+16 get R2 source
00001C08	E612 00B9 F058			1392+	VCVD	V1, R2, 159, 11 test instruction
00001C0E	E710 8F08 000E		00001108	1393+	VST	V1, V10UTPUT save
00001C14	B98D 0020			1394+	EPSW	R2, R0 exptract psw
00001C18	5020 8EE4		000010E4	1395+	ST	R2, CCPSW to save CC
00001C1C	07FB			1396+	BR	R11 return
00001C20				1397+RE31	DC	0F
00001C20				1398+	DROP	R5
00001C20	00000000 00000000			1399	DC	XL16' 00000000000000000000000000000000F' V1 result
00001C28	00000000 0000000F					
00001C30	00000000 00000000			1400	DC	FD' 0' R2 source
				1401		
				1402	VRR_K	VCVD, 159, 11, 0
00001C38				1403+	DS	0FD
00001C38		00001C38		1404+	USING	*, R5 base for test data and test routine
00001C38	00001C54			1405+T32	DC	A(X32) address of test routine
00001C3C	0020			1406+	DC	H' 32' test number
00001C3E	00			1407+	DC	XL1' 00'
00001C3F	9F			1408+	DC	HL1' 159' i3
00001C40	0B			1409+	DC	HL1' 11' m4
00001C41	00			1410+	DC	HL1' 0' cc
00001C42	07			1411+	DC	HL1' 7' cc failed mask
00001C43	E5C3E5C4 40404040			1412+	DC	CL8' VCVD' instruction name
00001C4C	00000010			1413+	DC	A(16) result length
00001C50	00001C78			1414+REA32	DC	A(RE32) result address
				1415+*		INSTRUCTION UNDER TEST ROUTINE
00001C54				1416+X32	DS	0F
00001C54	E710 8F40 0006		00001140	1417+	VL	V1, V1FUDGE pollute V1
00001C5A	E320 5050 0004		00001C88	1418+	LG	R2, RE32+16 get R2 source
00001C60	E612 00B9 F058			1419+	VCVD	V1, R2, 159, 11 test instruction
00001C66	E710 8F08 000E		00001108	1420+	VST	V1, V10UTPUT save
00001C6C	B98D 0020			1421+	EPSW	R2, R0 exptract psw
00001C70	5020 8EE4		000010E4	1422+	ST	R2, CCPSW to save CC
00001C74	07FB			1423+	BR	R11 return
00001C78				1424+RE32	DC	0F
00001C78				1425+	DROP	R5
00001C78	00000000 00000000			1426	DC	XL16' 000000000000000000000000000000001F' V1 result
00001C80	00000000 0000001F					
00001C88	00000000 00000001			1427	DC	FD' 1' R2 source
				1428		
				1429	VRR_K	VCVD, 159, 11, 0
00001C90				1430+	DS	0FD
00001C90		00001C90		1431+	USING	*, R5 base for test data and test routine
00001C90	00001CAC			1432+T33	DC	A(X33) address of test routine

UINT_MAX

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C94	0021			1433+	DC	H' 33'	test number
00001C96	00			1434+	DC	XL1' 00'	
00001C97	9F			1435+	DC	HL1' 159'	i3
00001C98	0B			1436+	DC	HL1' 11'	m4
00001C99	00			1437+	DC	HL1' 0'	cc
00001C9A	07			1438+	DC	HL1' 7'	cc failed mask
00001C9B	E5C3E5C4 40404040			1439+	DC	CL8' VCVD'	instruction name
00001CA4	00000010			1440+	DC	A(16)	result length
00001CA8	00001CD0			1441+REA33	DC	A(RE33)	result address
				1442+*			INSTRUCTION UNDER TEST ROUTINE
00001CAC				1443+X33	DS	0F	
00001CAC	E710 8F40 0006		00001140	1444+	VL	V1, V1FUDGE	pollute V1
00001CB2	E320 5050 0004		00001CE0	1445+	LG	R2, RE33+16	get R2 source
00001CB8	E612 00B9 F058			1446+	VCVD	V1, R2, 159, 11	test instruction
00001CBE	E710 8F08 000E		00001108	1447+	VST	V1, V10UTPUT	save
00001CC4	B98D 0020			1448+	EPSW	R2, R0	exptract psw
00001CC8	5020 8EE4		000010E4	1449+	ST	R2, CCPSW	to save CC
00001CCC	07FB			1450+	BR	R11	return
00001CD0				1451+RE33	DC	0F	
00001CD0				1452+	DROP	R5	
00001CD0	00000000 00000000			1453	DC	XL16' 0000000000000000000000004294967295F'	V1 result
00001CD8	00000429 4967295F						
00001CE0	FFFFFFFF FFFFFFFF			1454	DC	FD' - 1'	R2 source
				1455			
				1456	VRR_K	VCVD, 159, 11, 0	INT_MAX
00001CE8				1457+	DS	0FD	
00001CE8		00001CE8		1458+	USING	*, R5	base for test data and test routine
00001CE8	00001D04			1459+T34	DC	A(X34)	address of test routine
00001CEC	0022			1460+	DC	H' 34'	test number
00001CEE	00			1461+	DC	XL1' 00'	
00001CEF	9F			1462+	DC	HL1' 159'	i3
00001CF0	0B			1463+	DC	HL1' 11'	m4
00001CF1	00			1464+	DC	HL1' 0'	cc
00001CF2	07			1465+	DC	HL1' 7'	cc failed mask
00001CF3	E5C3E5C4 40404040			1466+	DC	CL8' VCVD'	instruction name
00001CFC	00000010			1467+	DC	A(16)	result length
00001D00	00001D28			1468+REA34	DC	A(RE34)	result address
				1469+*			INSTRUCTION UNDER TEST ROUTINE
00001D04				1470+X34	DS	0F	
00001D04	E710 8F40 0006		00001140	1471+	VL	V1, V1FUDGE	pollute V1
00001D0A	E320 5050 0004		00001D38	1472+	LG	R2, RE34+16	get R2 source
00001D10	E612 00B9 F058			1473+	VCVD	V1, R2, 159, 11	test instruction
00001D16	E710 8F08 000E		00001108	1474+	VST	V1, V10UTPUT	save
00001D1C	B98D 0020			1475+	EPSW	R2, R0	exptract psw
00001D20	5020 8EE4		000010E4	1476+	ST	R2, CCPSW	to save CC
00001D24	07FB			1477+	BR	R11	return
00001D28				1478+RE34	DC	0F	
00001D28				1479+	DROP	R5	
00001D28	00000000 00000000			1480	DC	XL16' 0000000000000000000000002147483647F'	V1 result
00001D30	00000214 7483647F						
00001D38	00000000 7FFFFFFF			1481	DC	FD' 2147483647'	R2 source
				1482			
				1483	VRR_K	VCVD, 159, 11, 0	INT_MIN
00001D40				1484+	DS	0FD	
00001D40		00001D40		1485+	USING	*, R5	base for test data and test routine
00001D40	00001D5C			1486+T35	DC	A(X35)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D44	0023			1487+	DC	H' 35'	test number
00001D46	00			1488+	DC	XL1' 00'	
00001D47	9F			1489+	DC	HL1' 159'	i3
00001D48	0B			1490+	DC	HL1' 11'	m4
00001D49	00			1491+	DC	HL1' 0'	cc
00001D4A	07			1492+	DC	HL1' 7'	cc failed mask
00001D4B	E5C3E5C4 40404040			1493+	DC	CL8' VCVD'	instruction name
00001D54	00000010			1494+	DC	A(16)	result length
00001D58	00001D80			1495+REA35	DC	A(RE35)	result address
				1496+*			INSTRUCTION UNDER TEST ROUTINE
00001D5C				1497+X35	DS	0F	
00001D5C	E710 8F40 0006		00001140	1498+	VL	V1, V1FUDGE	pollute V1
00001D62	E320 5050 0004		00001D90	1499+	LG	R2, RE35+16	get R2 source
00001D68	E612 00B9 F058			1500+	VCVD	V1, R2, 159, 11	test instruction
00001D6E	E710 8F08 000E		00001108	1501+	VST	V1, V10UTPUT	save
00001D74	B98D 0020			1502+	EPSW	R2, R0	exptract psw
00001D78	5020 8EE4		000010E4	1503+	ST	R2, CCPSW	to save CC
00001D7C	07FB			1504+	BR	R11	return
00001D80				1505+RE35	DC	0F	
00001D80				1506+	DROP	R5	
00001D80	00000000 00000000			1507	DC	XL16' 00000000000000000000000002147483648F'	V1 result
00001D88	00000214 7483648F						
00001D90	FFFFFFFF 80000000			1508	DC	FD' - 2147483648'	R2 source
				1509			
				1510 * VCVD		m4= 11 (LB=1, P1=1 , CS=1)	
				1511 *		i3= 137 (IOM=1, RDC= 9)	
				1512			
				1513	VRR_K	VCVD, 137, 11, 0	
00001D98				1514+	DS	0FD	
00001D98		00001D98		1515+	USING	*, R5	base for test data and test routine
00001D98	00001DB4			1516+T36	DC	A(X36)	address of test routine
00001D9C	0024			1517+	DC	H' 36'	test number
00001D9E	00			1518+	DC	XL1' 00'	
00001D9F	89			1519+	DC	HL1' 137'	i3
00001DA0	0B			1520+	DC	HL1' 11'	m4
00001DA1	00			1521+	DC	HL1' 0'	cc
00001DA2	07			1522+	DC	HL1' 7'	cc failed mask
00001DA3	E5C3E5C4 40404040			1523+	DC	CL8' VCVD'	instruction name
00001DAC	00000010			1524+	DC	A(16)	result length
00001DB0	00001DD8			1525+REA36	DC	A(RE36)	result address
				1526+*			INSTRUCTION UNDER TEST ROUTINE
00001DB4				1527+X36	DS	0F	
00001DB4	E710 8F40 0006		00001140	1528+	VL	V1, V1FUDGE	pollute V1
00001DBA	E320 5050 0004		00001DE8	1529+	LG	R2, RE36+16	get R2 source
00001DC0	E612 00B8 9058			1530+	VCVD	V1, R2, 137, 11	test instruction
00001DC6	E710 8F08 000E		00001108	1531+	VST	V1, V10UTPUT	save
00001DCC	B98D 0020			1532+	EPSW	R2, R0	exptract psw
00001DD0	5020 8EE4		000010E4	1533+	ST	R2, CCPSW	to save CC
00001DD4	07FB			1534+	BR	R11	return
00001DD8				1535+RE36	DC	0F	
00001DD8				1536+	DROP	R5	
00001DD8	00000000 00000000			1537	DC	XL16' 00000000000000000000000000000000F'	V1 result
00001DE0	00000000 0000000F						
00001DE8	00000000 00000000			1538	DC	FD' 0'	R2 source
				1539			
				1540	VRR_K	VCVD, 137, 11, 0	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1649 *	-----
				1650 * VCDVG	- VECTOR CONVERT TO DECIMAL (64)
				1651 *	-----
				1652 * VCDVG simple	m4= 1 (LB=0, P1=0 , CS=1)
				1653 *	m4= 3 (LB=0, P1=1 , CS=1)
				1654 *	m4= 9 (LB=1, P1=0 , CS=1)
				1655 *	m4= 11 (LB=1, P1=1 , CS=1)
				1656 *	
				1657 *	i3= 137 (IOM=1, RDC= 9)
				1658 *	i3= 159 (IOM=1, RDC=31)
				1659 *	
				1660 * VCDVG	m4= 1 (LB=0, P1=0 , CS=1)
				1661 *	i3= 159 (IOM=1, RDC=31)
				1662	
				1663	VRR_K VCDVG, 159, 1, 0
00001F50				1664+	DS OFD
00001F50		00001F50		1665+	USING *, R5
00001F50	00001F6C			1666+T41	DC A(X41)
00001F54	0029			1667+	DC H' 41'
00001F56	00			1668+	DC XL1' 00'
00001F57	9F			1669+	DC HL1' 159'
00001F58	01			1670+	DC HL1' 1'
00001F59	00			1671+	DC HL1' 0'
00001F5A	07			1672+	DC HL1' 7'
00001F5B	E5C3E5C4 C7404040			1673+	DC CL8' VCDVG'
00001F64	00000010			1674+	DC A(16)
00001F68	00001F90			1675+REA41	DC A(RE41)
				1676+*	INSTRUCTION UNDER TEST ROUTINE
00001F6C				1677+X41	DS OF
00001F6C	E710 8F40 0006		00001140	1678+	VL V1, V1FUDGE
00001F72	E320 5050 0004		00001FA0	1679+	LG R2, RE41+16
00001F78	E612 0019 F05A			1680+	VCDVG V1, R2, 159, 1
00001F7E	E710 8F08 000E		00001108	1681+	VST V1, V10UTPUT
00001F84	B98D 0020			1682+	EPSW R2, R0
00001F88	5020 8EE4		000010E4	1683+	ST R2, CCPSW
00001F8C	07FB			1684+	BR R11
00001F90				1685+RE41	DC OF
00001F90				1686+	DROP R5
00001F90	00000000 00000000			1687	DC XL16' 00000000000000000000000000000000C'
00001F98	00000000 0000000C				
00001FA0	00000000 00000000			1688	DC FD' 0'
				1689	
				1690	VRR_K VCDVG, 159, 1, 0
00001FA8				1691+	DS OFD
00001FA8		00001FA8		1692+	USING *, R5
00001FA8	00001FC4			1693+T42	DC A(X42)
00001FAC	002A			1694+	DC H' 42'
00001FAE	00			1695+	DC XL1' 00'
00001FAF	9F			1696+	DC HL1' 159'
00001FB0	01			1697+	DC HL1' 1'
00001FB1	00			1698+	DC HL1' 0'
00001FB2	07			1699+	DC HL1' 7'
00001FB3	E5C3E5C4 C7404040			1700+	DC CL8' VCDVG'
00001FBC	00000010			1701+	DC A(16)
00001FC0	00001FE8			1702+REA42	DC A(RE42)
				1703+*	INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002074				1758+X44	DS	0F	
00002074	E710 8F40 0006		00001140	1759+	VL	V1, V1FUDGE	pollute V1
0000207A	E320 5050 0004		000020A8	1760+	LG	R2, RE44+16	get R2 source
00002080	E612 0019 F05A			1761+	VCVDG	V1, R2, 159, 1	test instruction
00002086	E710 8F08 000E		00001108	1762+	VST	V1, V10UTPUT	save
0000208C	B98D 0020			1763+	EPSW	R2, R0	exptract psw
00002090	5020 8EE4		000010E4	1764+	ST	R2, CCPSW	to save CC
00002094	07FB			1765+	BR	R11	return
00002098				1766+RE44	DC	0F	
00002098				1767+	DROP	R5	
00002098	00000000 00000000			1768	DC	XL16' 0000000000000000000000002147483647C'	V1 result
000020A0	00000214 7483647C						
000020A8	00000000 7FFFFFFF			1769	DC	FD' 2147483647'	R2 source
				1770			
				1771	VRR_K	VCVDG, 159, 1, 0	INT_MIN
000020B0				1772+	DS	0FD	
000020B0		000020B0		1773+	USING	*, R5	base for test data and test routine
000020B0	000020CC			1774+T45	DC	A(X45)	address of test routine
000020B4	002D			1775+	DC	H' 45'	test number
000020B6	00			1776+	DC	XL1' 00'	
000020B7	9F			1777+	DC	HL1' 159'	i3
000020B8	01			1778+	DC	HL1' 1'	m4
000020B9	00			1779+	DC	HL1' 0'	cc
000020BA	07			1780+	DC	HL1' 7'	cc failed mask
000020BB	E5C3E5C4 C7404040			1781+	DC	CL8' VCVDG'	instruction name
000020C4	00000010			1782+	DC	A(16)	result length
000020C8	000020F0			1783+REA45	DC	A(RE45)	result address
				1784+*			INSTRUCTION UNDER TEST ROUTINE
000020CC				1785+X45	DS	0F	
000020CC	E710 8F40 0006		00001140	1786+	VL	V1, V1FUDGE	pollute V1
000020D2	E320 5050 0004		00002100	1787+	LG	R2, RE45+16	get R2 source
000020D8	E612 0019 F05A			1788+	VCVDG	V1, R2, 159, 1	test instruction
000020DE	E710 8F08 000E		00001108	1789+	VST	V1, V10UTPUT	save
000020E4	B98D 0020			1790+	EPSW	R2, R0	exptract psw
000020E8	5020 8EE4		000010E4	1791+	ST	R2, CCPSW	to save CC
000020EC	07FB			1792+	BR	R11	return
000020F0				1793+RE45	DC	0F	
000020F0				1794+	DROP	R5	
000020F0	00000000 00000000			1795	DC	XL16' 0000000000000000000000002147483648D'	V1 result
000020F8	00000214 7483648D						
00002100	FFFFFFFF 80000000			1796	DC	FD' - 2147483648'	R2 source
				1797			
				1798	VRR_K	VCVDG, 159, 1, 0	LONG_MAX
00002108				1799+	DS	0FD	
00002108		00002108		1800+	USING	*, R5	base for test data and test routine
00002108	00002124			1801+T46	DC	A(X46)	address of test routine
0000210C	002E			1802+	DC	H' 46'	test number
0000210E	00			1803+	DC	XL1' 00'	
0000210F	9F			1804+	DC	HL1' 159'	i3
00002110	01			1805+	DC	HL1' 1'	m4
00002111	00			1806+	DC	HL1' 0'	cc
00002112	07			1807+	DC	HL1' 7'	cc failed mask
00002113	E5C3E5C4 C7404040			1808+	DC	CL8' VCVDG'	instruction name
0000211C	00000010			1809+	DC	A(16)	result length
00002120	00002148			1810+REA46	DC	A(RE46)	result address
				1811+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002124				1812+X46	DS	0F	
00002124	E710 8F40 0006		00001140	1813+	VL	V1, V1FUDGE	pollute V1
0000212A	E320 5050 0004		00002158	1814+	LG	R2, RE46+16	get R2 source
00002130	E612 0019 F05A			1815+	VCVDG	V1, R2, 159, 1	test instruction
00002136	E710 8F08 000E		00001108	1816+	VST	V1, V10UTPUT	save
0000213C	B98D 0020			1817+	EPSW	R2, R0	exptract psw
00002140	5020 8EE4		000010E4	1818+	ST	R2, CCPSW	to save CC
00002144	07FB			1819+	BR	R11	return
00002148				1820+RE46	DC	0F	
00002148				1821+	DROP	R5	
00002148	00000000 00009223			1822	DC	XL16' 00000000000009223372036854775807C'	V1 source
00002150	37203685 4775807C						
00002158	7FFFFFFF FFFFFFFF			1823	DC	XL08' 7FFFFFFF'	R1 result
				1824			
				1825	VRR_K	VCVDG, 159, 1, 0	LONG_MIN
00002160				1826+	DS	0FD	
00002160		00002160		1827+	USING	*, R5	base for test data and test routine
00002160	0000217C			1828+T47	DC	A(X47)	address of test routine
00002164	002F			1829+	DC	H' 47'	test number
00002166	00			1830+	DC	XL1' 00'	
00002167	9F			1831+	DC	HL1' 159'	i3
00002168	01			1832+	DC	HL1' 1'	m4
00002169	00			1833+	DC	HL1' 0'	cc
0000216A	07			1834+	DC	HL1' 7'	cc failed mask
0000216B	E5C3E5C4 C7404040			1835+	DC	CL8' VCVDG'	instruction name
00002174	00000010			1836+	DC	A(16)	result length
00002178	000021A0			1837+REA47	DC	A(RE47)	result address
				1838+*			INSTRUCTION UNDER TEST ROUTINE
0000217C				1839+X47	DS	0F	
0000217C	E710 8F40 0006		00001140	1840+	VL	V1, V1FUDGE	pollute V1
00002182	E320 5050 0004		000021B0	1841+	LG	R2, RE47+16	get R2 source
00002188	E612 0019 F05A			1842+	VCVDG	V1, R2, 159, 1	test instruction
0000218E	E710 8F08 000E		00001108	1843+	VST	V1, V10UTPUT	save
00002194	B98D 0020			1844+	EPSW	R2, R0	exptract psw
00002198	5020 8EE4		000010E4	1845+	ST	R2, CCPSW	to save CC
0000219C	07FB			1846+	BR	R11	return
000021A0				1847+RE47	DC	0F	
000021A0				1848+	DROP	R5	
000021A0	00000000 00009223			1849	DC	XL16' 00000000000009223372036854775808D'	V1 source
000021A8	37203685 4775808D						
000021B0	80000000 00000000			1850	DC	XL08' 8000000000000000'	R1 result
				1851			
				1852	VRR_K	VCVDG, 159, 1, 0	ULONG_MAX
000021B8				1853+	DS	0FD	
000021B8		000021B8		1854+	USING	*, R5	base for test data and test routine
000021B8	000021D4			1855+T48	DC	A(X48)	address of test routine
000021BC	0030			1856+	DC	H' 48'	test number
000021BE	00			1857+	DC	XL1' 00'	
000021BF	9F			1858+	DC	HL1' 159'	i3
000021C0	01			1859+	DC	HL1' 1'	m4
000021C1	00			1860+	DC	HL1' 0'	cc
000021C2	07			1861+	DC	HL1' 7'	cc failed mask
000021C3	E5C3E5C4 C7404040			1862+	DC	CL8' VCVDG'	instruction name
000021CC	00000010			1863+	DC	A(16)	result length
000021D0	000021F8			1864+REA48	DC	A(RE48)	result address
				1865+*			INSTRUCTION UNDER TEST ROUTINE

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LOC	OBJECT CODE		ADDR1	ADDR2	STMT		
0000232C	00000010				1974+	DC	A(16)
00002330	00002358				1975+REA52	DC	A(RE52)
					1976+*		result length
					1977+X52	DS	OF
00002334	E710 8F40 0006			00001140	1978+	VL	V1, V1FUDGE
0000233A	E320 5050 0004			00002368	1979+	LG	R2, RE52+16
00002340	E612 0018 905A				1980+	VCVDG	V1, R2, 137, 1
00002346	E710 8F08 000E			00001108	1981+	VST	V1, V10UTPUT
0000234C	B98D 0020				1982+	EPSW	R2, R0
00002350	5020 8EE4			000010E4	1983+	ST	R2, CCPSW
00002354	07FB				1984+	BR	R11
					1985+RE52	DC	OF
00002358					1986+	DROP	R5
00002358	00000000 00000000				1987	DC	XL16' 000000000000000000000000147483647C'
00002360	00000014 7483647C						V1 result
00002368	00000000 7FFFFFFF				1988	DC	FD' 2147483647'
					1989		R2 source
					1990	VRR_K	VCVDG, 137, 1, 3
00002370					1991+	DS	OFD
00002370			00002370		1992+	USING	*, R5
00002370	0000238C				1993+T53	DC	A(X53)
00002374	0035				1994+	DC	H' 53'
00002376	00				1995+	DC	XL1' 00'
00002377	89				1996+	DC	HL1' 137'
00002378	01				1997+	DC	HL1' 1'
00002379	03				1998+	DC	HL1' 3'
0000237A	0E				1999+	DC	HL1' 14'
0000237B	E5C3E5C4 C7404040				2000+	DC	CL8' VCVDG'
00002384	00000010				2001+	DC	A(16)
00002388	000023B0				2002+REA53	DC	A(RE53)
					2003+*		result address
					2004+X53	DS	OF
0000238C	E710 8F40 0006			00001140	2005+	VL	V1, V1FUDGE
0000238C	E320 5050 0004			000023C0	2006+	LG	R2, RE53+16
00002392	E612 0018 905A				2007+	VCVDG	V1, R2, 137, 1
0000239E	E710 8F08 000E			00001108	2008+	VST	V1, V10UTPUT
000023A4	B98D 0020				2009+	EPSW	R2, R0
000023A8	5020 8EE4			000010E4	2010+	ST	R2, CCPSW
000023AC	07FB				2011+	BR	R11
					2012+RE53	DC	OF
000023B0					2013+	DROP	R5
000023B0	00000000 00000000				2014	DC	XL16' 000000000000000000000000147483648D'
000023B8	00000014 7483648D						V1 result
000023C0	FFFFFFFF 80000000				2015	DC	FD' - 2147483648'
					2016		
					2017	VRR_K	VCVDG, 137, 1, 3
000023C8					2018+	DS	OFD
000023C8			000023C8		2019+	USING	*, R5
000023C8	000023E4				2020+T54	DC	A(X54)
000023CC	0036				2021+	DC	H' 54'
000023CE	00				2022+	DC	XL1' 00'
000023CF	89				2023+	DC	HL1' 137'
000023D0	01				2024+	DC	HL1' 1'
000023D1	03				2025+	DC	HL1' 3'
000023D2	0E				2026+	DC	HL1' 14'
000023D3	E5C3E5C4 C7404040				2027+	DC	CL8' VCVDG'
							cc failed mask
							instruction name
							LONG_MAX
							base for test data and test routine
							address of test routine
							test number
							i3
							m4
							cc
							cc failed mask
							instruction name
							result length
							result address
							INSTRUCTION UNDER TEST ROUTINE
							pollute V1
							get R2 source
							test instruction
							save
							exptract psw
							to save CC
							return

ASMA Ver. 0.7.0 zvector-e6-13-converttodecimal (Zvector E6 VRI-i)					02 Jun 2024 16:00:20 Page 43		
LOC	OBJECT CODE		ADDR1	ADDR2	STMT		
000023DC	00000010				2028+	DC	A(16)
000023E0	00002408				2029+REA54	DC	A(RE54)
					2030+*		result length
000023E4					2031+X54	DS	OF
000023E4	E710	8F40 0006		00001140	2032+	VL	V1, V1FUDGE
000023EA	E320	5050 0004		00002418	2033+	LG	R2, RE54+16
000023F0	E612	0018 905A			2034+	VCVDG	V1, R2, 137, 1
000023F6	E710	8F08 000E		00001108	2035+	VST	V1, V10UTPUT
000023FC	B98D	0020			2036+	EPSW	R2, R0
00002400	5020	8EE4		000010E4	2037+	ST	R2, CCPSW
00002404	07FB				2038+	BR	R11
00002408					2039+RE54	DC	OF
00002408					2040+	DROP	R5
00002408	00000000	00000000			2041	DC	XL16' 000000000000000000000000854775807C'
00002410	00000085	4775807C					V1 source
00002418	7FFFFFFF	FFFFFFFF			2042	DC	XL08' 7FFFFFFFFFFFFFFFFF'
					2043		R1 result
					2044	VRR_K	VCVDG, 137, 1, 3
00002420					2045+	DS	OFD
00002420			00002420		2046+	USING	*, R5
00002420	0000243C				2047+T55	DC	A(X55)
00002424	0037				2048+	DC	H' 55'
00002426	00				2049+	DC	XL1' 00'
00002427	89				2050+	DC	HL1' 137'
00002428	01				2051+	DC	HL1' 1'
00002429	03				2052+	DC	HL1' 3'
0000242A	0E				2053+	DC	HL1' 14'
0000242B	E5C3E5C4	C7404040			2054+	DC	CL8' VCVDG'
00002434	00000010				2055+	DC	A(16)
00002438	00002460				2056+REA55	DC	A(RE55)
					2057+*		result length
0000243C					2058+X55	DS	OF
0000243C	E710	8F40 0006		00001140	2059+	VL	V1, V1FUDGE
00002442	E320	5050 0004		00002470	2060+	LG	R2, RE55+16
00002448	E612	0018 905A			2061+	VCVDG	V1, R2, 137, 1
0000244E	E710	8F08 000E		00001108	2062+	VST	V1, V10UTPUT
00002454	B98D	0020			2063+	EPSW	R2, R0
00002458	5020	8EE4		000010E4	2064+	ST	R2, CCPSW
0000245C	07FB				2065+	BR	R11
00002460					2066+RE55	DC	OF
00002460					2067+	DROP	R5
00002460	00000000	00000000			2068	DC	XL16' 000000000000000000000000854775808D'
00002468	00000085	4775808D					V1 source
00002470	80000000	00000000			2069	DC	XL08' 8000000000000000'
					2070		R1 result
					2071	VRR_K	VCVDG, 137, 1, 0
00002478					2072+	DS	OFD
00002478			00002478		2073+	USING	*, R5
00002478	00002494				2074+T56	DC	A(X56)
0000247C	0038				2075+	DC	H' 56'
0000247E	00				2076+	DC	XL1' 00'
0000247F	89				2077+	DC	HL1' 137'
00002480	01				2078+	DC	HL1' 1'
00002481	00				2079+	DC	HL1' 0'
00002482	07				2080+	DC	HL1' 7'
00002483	E5C3E5C4	C7404040			2081+	DC	CL8' VCVDG'
							cc failed mask
							instruction name
							base for test data and test routine
							address of test routine
							test number
							i3
							m4
							cc
							cc failed mask
							instruction name
							result length
							result address
							INSTRUCTION UNDER TEST ROUTINE
							pollute V1
							get R2 source
							test instruction
							save
							exptract psw
							to save CC
							return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000025E0	03			2190+	DC	HL1' 3'	m4
000025E1	00			2191+	DC	HL1' 0'	cc
000025E2	07			2192+	DC	HL1' 7'	cc failed mask
000025E3	E5C3E5C4 C7404040			2193+	DC	CL8' VCVDG'	instruction name
000025EC	00000010			2194+	DC	A(16)	result length
000025F0	00002618			2195+REA60	DC	A(RE60)	result address
				2196+*			INSTRUCTION UNDER TEST ROUTINE
000025F4				2197+X60	DS	0F	
000025F4	E710 8F40 0006		00001140	2198+	VL	V1, V1FUDGE	pollute V1
000025FA	E320 5050 0004		00002628	2199+	LG	R2, RE60+16	get R2 source
00002600	E612 0039 F05A			2200+	VCVDG	V1, R2, 159, 3	test instruction
00002606	E710 8F08 000E		00001108	2201+	VST	V1, V10UTPUT	save
0000260C	B98D 0020			2202+	EPSW	R2, R0	exptract psw
00002610	5020 8EE4		000010E4	2203+	ST	R2, CCPSW	to save CC
00002614	07FB			2204+	BR	R11	return
00002618				2205+RE60	DC	0F	
00002618				2206+	DROP	R5	
00002618	00000000 00000000			2207	DC	XL16' 0000000000000000000000002147483647F'	V1 result
00002620	00000214 7483647F						
00002628	00000000 7FFFFFFF			2208	DC	FD' 2147483647'	R2 source
				2209			
				2210	VRR_K	VCVDG, 159, 3, 0	INT_MIN
00002630				2211+	DS	0FD	
00002630		00002630		2212+	USING	*, R5	base for test data and test routine
00002630	0000264C			2213+T61	DC	A(X61)	address of test routine
00002634	003D			2214+	DC	H' 61'	test number
00002636	00			2215+	DC	XL1' 00'	
00002637	9F			2216+	DC	HL1' 159'	i3
00002638	03			2217+	DC	HL1' 3'	m4
00002639	00			2218+	DC	HL1' 0'	cc
0000263A	07			2219+	DC	HL1' 7'	cc failed mask
0000263B	E5C3E5C4 C7404040			2220+	DC	CL8' VCVDG'	instruction name
00002644	00000010			2221+	DC	A(16)	result length
00002648	00002670			2222+REA61	DC	A(RE61)	result address
				2223+*			INSTRUCTION UNDER TEST ROUTINE
0000264C				2224+X61	DS	0F	
0000264C	E710 8F40 0006		00001140	2225+	VL	V1, V1FUDGE	pollute V1
00002652	E320 5050 0004		00002680	2226+	LG	R2, RE61+16	get R2 source
00002658	E612 0039 F05A			2227+	VCVDG	V1, R2, 159, 3	test instruction
0000265E	E710 8F08 000E		00001108	2228+	VST	V1, V10UTPUT	save
00002664	B98D 0020			2229+	EPSW	R2, R0	exptract psw
00002668	5020 8EE4		000010E4	2230+	ST	R2, CCPSW	to save CC
0000266C	07FB			2231+	BR	R11	return
00002670				2232+RE61	DC	0F	
00002670				2233+	DROP	R5	
00002670	00000000 00000000			2234	DC	XL16' 0000000000000000000000002147483648F'	V1 result
00002678	00000214 7483648F						
00002680	FFFFFFFF 80000000			2235	DC	FD' - 2147483648'	R2 source
				2236			
				2237	VRR_K	VCVDG, 159, 3, 0	LONG_MAX
00002688				2238+	DS	0FD	
00002688		00002688		2239+	USING	*, R5	base for test data and test routine
00002688	000026A4			2240+T62	DC	A(X62)	address of test routine
0000268C	003E			2241+	DC	H' 62'	test number
0000268E	00			2242+	DC	XL1' 00'	
0000268F	9F			2243+	DC	HL1' 159'	i3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002690	03			2244+	DC	HL1' 3'	m4
00002691	00			2245+	DC	HL1' 0'	cc
00002692	07			2246+	DC	HL1' 7'	cc failed mask
00002693	E5C3E5C4 C7404040			2247+	DC	CL8' VCVDG'	instruction name
0000269C	00000010			2248+	DC	A(16)	result length
000026A0	000026C8			2249+REA62	DC	A(RE62)	result address
				2250+*			INSTRUCTION UNDER TEST ROUTINE
000026A4				2251+X62	DS	0F	
000026A4	E710 8F40 0006		00001140	2252+	VL	V1, V1FUDGE	pollute V1
000026AA	E320 5050 0004		000026D8	2253+	LG	R2, RE62+16	get R2 source
000026B0	E612 0039 F05A			2254+	VCVDG	V1, R2, 159, 3	test instruction
000026B6	E710 8F08 000E		00001108	2255+	VST	V1, V10UTPUT	save
000026BC	B98D 0020			2256+	EPSW	R2, R0	exptract psw
000026C0	5020 8EE4		000010E4	2257+	ST	R2, CCPSW	to save CC
000026C4	07FB			2258+	BR	R11	return
000026C8				2259+RE62	DC	0F	
000026C8				2260+	DROP	R5	
000026C8	00000000 00009223			2261	DC	XL16' 00000000000009223372036854775807F'	V1 source
000026D0	37203685 4775807F						
000026D8	7FFFFFFF FFFFFFFF			2262	DC	XL08' 7FFFFFFF FFFFFFFF'	R1 result
				2263			
				2264	VRR_K	VCVDG, 159, 3, 0	LONG_MIN
000026E0				2265+	DS	0FD	
000026E0		000026E0		2266+	USING	*, R5	base for test data and test routine
000026E0	000026FC			2267+T63	DC	A(X63)	address of test routine
000026E4	003F			2268+	DC	H' 63'	test number
000026E6	00			2269+	DC	XL1' 00'	
000026E7	9F			2270+	DC	HL1' 159'	i3
000026E8	03			2271+	DC	HL1' 3'	m4
000026E9	00			2272+	DC	HL1' 0'	cc
000026EA	07			2273+	DC	HL1' 7'	cc failed mask
000026EB	E5C3E5C4 C7404040			2274+	DC	CL8' VCVDG'	instruction name
000026F4	00000010			2275+	DC	A(16)	result length
000026F8	00002720			2276+REA63	DC	A(RE63)	result address
				2277+*			INSTRUCTION UNDER TEST ROUTINE
000026FC				2278+X63	DS	0F	
000026FC	E710 8F40 0006		00001140	2279+	VL	V1, V1FUDGE	pollute V1
00002702	E320 5050 0004		00002730	2280+	LG	R2, RE63+16	get R2 source
00002708	E612 0039 F05A			2281+	VCVDG	V1, R2, 159, 3	test instruction
0000270E	E710 8F08 000E		00001108	2282+	VST	V1, V10UTPUT	save
00002714	B98D 0020			2283+	EPSW	R2, R0	exptract psw
00002718	5020 8EE4		000010E4	2284+	ST	R2, CCPSW	to save CC
0000271C	07FB			2285+	BR	R11	return
00002720				2286+RE63	DC	0F	
00002720				2287+	DROP	R5	
00002720	00000000 00009223			2288	DC	XL16' 00000000000009223372036854775808F'	V1 source
00002728	37203685 4775808F						
00002730	80000000 00000000			2289	DC	XL08' 8000000000000000'	R1 result
				2290			
				2291	VRR_K	VCVDG, 159, 3, 0	ULONG_MAX
00002738				2292+	DS	0FD	
00002738		00002738		2293+	USING	*, R5	base for test data and test routine
00002738	00002754			2294+T64	DC	A(X64)	address of test routine
0000273C	0040			2295+	DC	H' 64'	test number
0000273E	00			2296+	DC	XL1' 00'	
0000273F	9F			2297+	DC	HL1' 159'	i3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000289C	0044			2406+	DC	H' 68' test number
0000289E	00			2407+	DC	XL1' 00'
0000289F	89			2408+	DC	HL1' 137' i3
000028A0	03			2409+	DC	HL1' 3' m4
000028A1	03			2410+	DC	HL1' 3' cc
000028A2	0E			2411+	DC	HL1' 14' cc failed mask
000028A3	E5C3E5C4 C7404040			2412+	DC	CL8' VCVDG' instruction name
000028AC	00000010			2413+	DC	A(16) result length
000028B0	000028D8			2414+REA68	DC	A(RE68) result address
				2415+*		INSTRUCTION UNDER TEST ROUTINE
000028B4				2416+X68	DS	0F
000028B4	E710 8F40 0006		00001140	2417+	VL	V1, V1FUDGE pollute V1
000028BA	E320 5050 0004		000028E8	2418+	LG	R2, RE68+16 get R2 source
000028C0	E612 0038 905A			2419+	VCVDG	V1, R2, 137, 3 test instruction
000028C6	E710 8F08 000E		00001108	2420+	VST	V1, V10UTPUT save
000028CC	B98D 0020			2421+	EPSW	R2, R0 exptract psw
000028D0	5020 8EE4		000010E4	2422+	ST	R2, CCPSW to save CC
000028D4	07FB			2423+	BR	R11 return
000028D8				2424+RE68	DC	0F
000028D8				2425+	DROP	R5
000028D8	00000000 00000000			2426	DC	XL16' 000000000000000000000000147483647F' V1 result
000028E0	00000014 7483647F					
000028E8	00000000 7FFFFFFF			2427	DC	FD' 2147483647' R2 source
				2428		
				2429	VRR_K	VCVDG, 137, 3, 3 INT_MIN
000028F0				2430+	DS	0FD
000028F0		000028F0		2431+	USING	*, R5 base for test data and test routine
000028F0	0000290C			2432+T69	DC	A(X69) address of test routine
000028F4	0045			2433+	DC	H' 69' test number
000028F6	00			2434+	DC	XL1' 00'
000028F7	89			2435+	DC	HL1' 137' i3
000028F8	03			2436+	DC	HL1' 3' m4
000028F9	03			2437+	DC	HL1' 3' cc
000028FA	0E			2438+	DC	HL1' 14' cc failed mask
000028FB	E5C3E5C4 C7404040			2439+	DC	CL8' VCVDG' instruction name
00002904	00000010			2440+	DC	A(16) result length
00002908	00002930			2441+REA69	DC	A(RE69) result address
				2442+*		INSTRUCTION UNDER TEST ROUTINE
0000290C				2443+X69	DS	0F
0000290C	E710 8F40 0006		00001140	2444+	VL	V1, V1FUDGE pollute V1
00002912	E320 5050 0004		00002940	2445+	LG	R2, RE69+16 get R2 source
00002918	E612 0038 905A			2446+	VCVDG	V1, R2, 137, 3 test instruction
0000291E	E710 8F08 000E		00001108	2447+	VST	V1, V10UTPUT save
00002924	B98D 0020			2448+	EPSW	R2, R0 exptract psw
00002928	5020 8EE4		000010E4	2449+	ST	R2, CCPSW to save CC
0000292C	07FB			2450+	BR	R11 return
00002930				2451+RE69	DC	0F
00002930				2452+	DROP	R5
00002930	00000000 00000000			2453	DC	XL16' 000000000000000000000000147483648F' V1 result
00002938	00000014 7483648F					
00002940	FFFFFFFF 80000000			2454	DC	FD' - 2147483648'
				2455		
				2456	VRR_K	VCVDG, 137, 3, 3 LONG_MAX
00002948				2457+	DS	0FD
00002948		00002948		2458+	USING	*, R5 base for test data and test routine
00002948	00002964			2459+T70	DC	A(X70) address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000294C	0046			2460+	DC	H' 70'	test number
0000294E	00			2461+	DC	XL1' 00'	
0000294F	89			2462+	DC	HL1' 137'	i3
00002950	03			2463+	DC	HL1' 3'	m4
00002951	03			2464+	DC	HL1' 3'	cc
00002952	0E			2465+	DC	HL1' 14'	cc failed mask
00002953	E5C3E5C4 C7404040			2466+	DC	CL8' VCVDG'	instruction name
0000295C	00000010			2467+	DC	A(16)	result length
00002960	00002988			2468+REA70	DC	A(RE70)	result address
				2469+*			INSTRUCTION UNDER TEST ROUTINE
00002964				2470+X70	DS	0F	
00002964	E710 8F40 0006		00001140	2471+	VL	V1, V1FUDGE	pollute V1
0000296A	E320 5050 0004		00002998	2472+	LG	R2, RE70+16	get R2 source
00002970	E612 0038 905A			2473+	VCVDG	V1, R2, 137, 3	test instruction
00002976	E710 8F08 000E		00001108	2474+	VST	V1, V10UTPUT	save
0000297C	B98D 0020			2475+	EPSW	R2, R0	exptract psw
00002980	5020 8EE4		000010E4	2476+	ST	R2, CCPSW	to save CC
00002984	07FB			2477+	BR	R11	return
00002988				2478+RE70	DC	0F	
00002988				2479+	DROP	R5	
00002988	00000000 00000000			2480	DC	XL16' 000000000000000000000000854775807F'	V1 source
00002990	00000085 4775807F						
00002998	7FFFFFFF FFFFFFFF			2481	DC	XL08' 7FFFFFFF	R1 result
				2482			
				2483	VRR_K	VCVDG, 137, 3, 3	LONG_MIN
000029A0				2484+	DS	0FD	
000029A0		000029A0		2485+	USING	*, R5	base for test data and test routine
000029A0	000029BC			2486+T71	DC	A(X71)	address of test routine
000029A4	0047			2487+	DC	H' 71'	test number
000029A6	00			2488+	DC	XL1' 00'	
000029A7	89			2489+	DC	HL1' 137'	i3
000029A8	03			2490+	DC	HL1' 3'	m4
000029A9	03			2491+	DC	HL1' 3'	cc
000029AA	0E			2492+	DC	HL1' 14'	cc failed mask
000029AB	E5C3E5C4 C7404040			2493+	DC	CL8' VCVDG'	instruction name
000029B4	00000010			2494+	DC	A(16)	result length
000029B8	000029E0			2495+REA71	DC	A(RE71)	result address
				2496+*			INSTRUCTION UNDER TEST ROUTINE
000029BC				2497+X71	DS	0F	
000029BC	E710 8F40 0006		00001140	2498+	VL	V1, V1FUDGE	pollute V1
000029C2	E320 5050 0004		000029F0	2499+	LG	R2, RE71+16	get R2 source
000029C8	E612 0038 905A			2500+	VCVDG	V1, R2, 137, 3	test instruction
000029CE	E710 8F08 000E		00001108	2501+	VST	V1, V10UTPUT	save
000029D4	B98D 0020			2502+	EPSW	R2, R0	exptract psw
000029D8	5020 8EE4		000010E4	2503+	ST	R2, CCPSW	to save CC
000029DC	07FB			2504+	BR	R11	return
000029E0				2505+RE71	DC	0F	
000029E0				2506+	DROP	R5	
000029E0	00000000 00000000			2507	DC	XL16' 000000000000000000000000854775808F'	V1 source
000029E8	00000085 4775808F						
000029F0	80000000 00000000			2508	DC	XL08' 8000000000000000	R1 result
				2509			
				2510	VRR_K	VCVDG, 137, 3, 0	ULONG_MAX
000029F8				2511+	DS	0FD	
000029F8		000029F8		2512+	USING	*, R5	base for test data and test routine
000029F8	00002A14			2513+T72	DC	A(X72)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002B58				2622	VRR_K	VCVDG, 159, 9, 0	INT_MAX
00002B58				2623+	DS	OFD	
00002B58		00002B58		2624+	USING	*, R5	base for test data and test routine
00002B58	00002B74			2625+T76	DC	A(X76)	address of test routine
00002B5C	004C			2626+	DC	H' 76'	test number
00002B5E	00			2627+	DC	XL1' 00'	
00002B5F	9F			2628+	DC	HL1' 159'	i3
00002B60	09			2629+	DC	HL1' 9'	m4
00002B61	00			2630+	DC	HL1' 0'	cc
00002B62	07			2631+	DC	HL1' 7'	cc failed mask
00002B63	E5C3E5C4 C7404040			2632+	DC	CL8' VCVDG'	instruction name
00002B6C	00000010			2633+	DC	A(16)	result length
00002B70	00002B98			2634+REA76	DC	A(RE76)	result address
				2635+*			INSTRUCTION UNDER TEST ROUTINE
00002B74				2636+X76	DS	OF	
00002B74	E710 8F40 0006		00001140	2637+	VL	V1, V1FUDGE	pollute V1
00002B7A	E320 5050 0004		00002BA8	2638+	LG	R2, RE76+16	get R2 source
00002B80	E612 0099 F05A			2639+	VCVDG	V1, R2, 159, 9	test instruction
00002B86	E710 8F08 000E		00001108	2640+	VST	V1, V10UTPUT	save
00002B8C	B98D 0020			2641+	EPSW	R2, R0	exptract psw
00002B90	5020 8EE4		000010E4	2642+	ST	R2, CCPSW	to save CC
00002B94	07FB			2643+	BR	R11	return
00002B98				2644+RE76	DC	OF	
00002B98				2645+	DROP	R5	
00002B98	00000000 00000000			2646	DC	XL16' 0000000000000000000000002147483647C'	V1 result
00002BA0	00000214 7483647C						
00002BA8	00000000 7FFFFFFF			2647	DC	FD' 2147483647'	R2 source
				2648			
				2649	VRR_K	VCVDG, 159, 9, 0	INT_MIN
00002BB0				2650+	DS	OFD	
00002BB0		00002BB0		2651+	USING	*, R5	base for test data and test routine
00002BB0	00002BCC			2652+T77	DC	A(X77)	address of test routine
00002BB4	004D			2653+	DC	H' 77'	test number
00002BB6	00			2654+	DC	XL1' 00'	
00002BB7	9F			2655+	DC	HL1' 159'	i3
00002BB8	09			2656+	DC	HL1' 9'	m4
00002BB9	00			2657+	DC	HL1' 0'	cc
00002BBA	07			2658+	DC	HL1' 7'	cc failed mask
00002BBB	E5C3E5C4 C7404040			2659+	DC	CL8' VCVDG'	instruction name
00002BC4	00000010			2660+	DC	A(16)	result length
00002BC8	00002BF0			2661+REA77	DC	A(RE77)	result address
				2662+*			INSTRUCTION UNDER TEST ROUTINE
00002BCC				2663+X77	DS	OF	
00002BCC	E710 8F40 0006		00001140	2664+	VL	V1, V1FUDGE	pollute V1
00002BD2	E320 5050 0004		00002C00	2665+	LG	R2, RE77+16	get R2 source
00002BD8	E612 0099 F05A			2666+	VCVDG	V1, R2, 159, 9	test instruction
00002BDE	E710 8F08 000E		00001108	2667+	VST	V1, V10UTPUT	save
00002BE4	B98D 0020			2668+	EPSW	R2, R0	exptract psw
00002BE8	5020 8EE4		000010E4	2669+	ST	R2, CCPSW	to save CC
00002BEC	07FB			2670+	BR	R11	return
00002BF0				2671+RE77	DC	OF	
00002BF0				2672+	DROP	R5	
00002BF0	00000000 00018446			2673	DC	XL16' 00000000000018446744071562067968C'	V1 result
00002BF8	74407156 2067968C						
00002C00	FFFFFFFF 80000000			2674	DC	XL8' FFFFFFFF80000000'	R2 source
				2675 *	DC	FD' - 2147483648'	R2 sourc

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2676		
				2677	VRR_K VCVDG, 159, 9, 0	LONG_MAX
00002C08				2678+	DS OFD	
00002C08		00002C08		2679+	USING *, R5	base for test data and test routine
00002C08	00002C24			2680+T78	DC A(X78)	address of test routine
00002C0C	004E			2681+	DC H' 78'	test number
00002C0E	00			2682+	DC XL1' 00'	
00002C0F	9F			2683+	DC HL1' 159'	i3
00002C10	09			2684+	DC HL1' 9'	m4
00002C11	00			2685+	DC HL1' 0'	cc
00002C12	07			2686+	DC HL1' 7'	cc failed mask
00002C13	E5C3E5C4 C7404040			2687+	DC CL8' VCVDG'	instruction name
00002C1C	00000010			2688+	DC A(16)	result length
00002C20	00002C48			2689+REA78	DC A(RE78)	result address
				2690+*		INSTRUCTION UNDER TEST ROUTINE
00002C24				2691+X78	DS OF	
00002C24	E710 8F40 0006		00001140	2692+	VL V1, V1FUDGE	pollute V1
00002C2A	E320 5050 0004		00002C58	2693+	LG R2, RE78+16	get R2 source
00002C30	E612 0099 F05A			2694+	VCVDG V1, R2, 159, 9	test instruction
00002C36	E710 8F08 000E		00001108	2695+	VST V1, V10UTPUT	save
00002C3C	B98D 0020			2696+	EPSW R2, R0	exptract psw
00002C40	5020 8EE4		000010E4	2697+	ST R2, CCPSW	to save CC
00002C44	07FB			2698+	BR R11	return
00002C48				2699+RE78	DC OF	
00002C48				2700+	DROP R5	
00002C48	00000000 00009223			2701	DC XL16' 00000000000009223372036854775807C'	V1 source
00002C50	37203685 4775807C					
00002C58	7FFFFFFF FFFFFFFF			2702	DC XL08' 7FFFFFFF'	R1 result
				2703		
				2704	VRR_K VCVDG, 159, 9, 0	LONG_MIN
00002C60				2705+	DS OFD	
00002C60		00002C60		2706+	USING *, R5	base for test data and test routine
00002C60	00002C7C			2707+T79	DC A(X79)	address of test routine
00002C64	004F			2708+	DC H' 79'	test number
00002C66	00			2709+	DC XL1' 00'	
00002C67	9F			2710+	DC HL1' 159'	i3
00002C68	09			2711+	DC HL1' 9'	m4
00002C69	00			2712+	DC HL1' 0'	cc
00002C6A	07			2713+	DC HL1' 7'	cc failed mask
00002C6B	E5C3E5C4 C7404040			2714+	DC CL8' VCVDG'	instruction name
00002C74	00000010			2715+	DC A(16)	result length
00002C78	00002CA0			2716+REA79	DC A(RE79)	result address
				2717+*		INSTRUCTION UNDER TEST ROUTINE
00002C7C				2718+X79	DS OF	
00002C7C	E710 8F40 0006		00001140	2719+	VL V1, V1FUDGE	pollute V1
00002C82	E320 5050 0004		00002CB0	2720+	LG R2, RE79+16	get R2 source
00002C88	E612 0099 F05A			2721+	VCVDG V1, R2, 159, 9	test instruction
00002C8E	E710 8F08 000E		00001108	2722+	VST V1, V10UTPUT	save
00002C94	B98D 0020			2723+	EPSW R2, R0	exptract psw
00002C98	5020 8EE4		000010E4	2724+	ST R2, CCPSW	to save CC
00002C9C	07FB			2725+	BR R11	return
00002CA0				2726+RE79	DC OF	
00002CA0				2727+	DROP R5	
00002CA0	00000000 00009223			2728	DC XL16' 00000000000009223372036854775808C'	V1 source
00002CA8	37203685 4775808C					
00002CB0	80000000 00000000			2729	DC XL08' 8000000000000000'	R1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2730		
				2731	VRR_K VCVDG, 159, 9, 0	ULONG_MAX
00002CB8				2732+	DS OFD	
00002CB8		00002CB8		2733+	USING *, R5	base for test data and test routine
00002CB8	00002CD4			2734+T80	DC A(X80)	address of test routine
00002CBC	0050			2735+	DC H' 80'	test number
00002CBE	00			2736+	DC XL1' 00'	
00002CBF	9F			2737+	DC HL1' 159'	i3
00002CC0	09			2738+	DC HL1' 9'	m4
00002CC1	00			2739+	DC HL1' 0'	cc
00002CC2	07			2740+	DC HL1' 7'	cc failed mask
00002CC3	E5C3E5C4 C7404040			2741+	DC CL8' VCVDG'	instruction name
00002CCC	00000010			2742+	DC A(16)	result length
00002CD0	00002CF8			2743+REA80	DC A(RE80)	result address
				2744+*		INSTRUCTION UNDER TEST ROUTINE
00002CD4				2745+X80	DS OF	
00002CD4	E710 8F40 0006		00001140	2746+	VL V1, V1FUDGE	pollute V1
00002CDA	E320 5050 0004		00002D08	2747+	LG R2, RE80+16	get R2 source
00002CE0	E612 0099 F05A			2748+	VCVDG V1, R2, 159, 9	test instruction
00002CE6	E710 8F08 000E		00001108	2749+	VST V1, V10UTPUT	save
00002CEC	B98D 0020			2750+	EPSW R2, R0	exptract psw
00002CF0	5020 8EE4		000010E4	2751+	ST R2, CCPSW	to save CC
00002CF4	07FB			2752+	BR R11	return
00002CF8				2753+RE80	DC OF	
00002CF8				2754+	DROP R5	
00002CF8	00000000 00018446			2755	DC XL16' 00000000000018446744073709551615C'	V1 source
00002D00	74407370 9551615C					
00002D08	FFFFFFFF FFFFFFFF			2756	DC XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				2757		
				2758 * VCVDG	m4= 9 (LB=1, P1=0 , CS=1)	
				2759 *	i3= 137 (IOM=1, RDC= 9)	
				2760		
				2761	VRR_K VCVDG, 137, 9, 0	
00002D10				2762+	DS OFD	
00002D10		00002D10		2763+	USING *, R5	base for test data and test routine
00002D10	00002D2C			2764+T81	DC A(X81)	address of test routine
00002D14	0051			2765+	DC H' 81'	test number
00002D16	00			2766+	DC XL1' 00'	
00002D17	89			2767+	DC HL1' 137'	i3
00002D18	09			2768+	DC HL1' 9'	m4
00002D19	00			2769+	DC HL1' 0'	cc
00002D1A	07			2770+	DC HL1' 7'	cc failed mask
00002D1B	E5C3E5C4 C7404040			2771+	DC CL8' VCVDG'	instruction name
00002D24	00000010			2772+	DC A(16)	result length
00002D28	00002D50			2773+REA81	DC A(RE81)	result address
				2774+*		INSTRUCTION UNDER TEST ROUTINE
00002D2C				2775+X81	DS OF	
00002D2C	E710 8F40 0006		00001140	2776+	VL V1, V1FUDGE	pollute V1
00002D32	E320 5050 0004		00002D60	2777+	LG R2, RE81+16	get R2 source
00002D38	E612 0098 905A			2778+	VCVDG V1, R2, 137, 9	test instruction
00002D3E	E710 8F08 000E		00001108	2779+	VST V1, V10UTPUT	save
00002D44	B98D 0020			2780+	EPSW R2, R0	exptract psw
00002D48	5020 8EE4		000010E4	2781+	ST R2, CCPSW	to save CC
00002D4C	07FB			2782+	BR R11	return
00002D50				2783+RE81	DC OF	
00002D50				2784+	DROP R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002D50	00000000 00000000			2785	DC	XL16' 00000000000000000000000000000000C'	V1 result
00002D58	00000000 0000000C						
00002D60	00000000 00000000			2786	DC	FD' 0'	R2 source
				2787			
				2788	VRR_K	VCVDG, 137, 9, 0	
00002D68				2789+	DS	OFD	
00002D68		00002D68		2790+	USING	*, R5	base for test data and test routine
00002D68	00002D84			2791+T82	DC	A(X82)	address of test routine
00002D6C	0052			2792+	DC	H' 82'	test number
00002D6E	00			2793+	DC	XL1' 00'	
00002D6F	89			2794+	DC	HL1' 137'	i3
00002D70	09			2795+	DC	HL1' 9'	m4
00002D71	00			2796+	DC	HL1' 0'	cc
00002D72	07			2797+	DC	HL1' 7'	cc failed mask
00002D73	E5C3E5C4 C7404040			2798+	DC	CL8' VCVDG'	instruction name
00002D7C	00000010			2799+	DC	A(16)	result length
00002D80	00002DA8			2800+REA82	DC	A(RE82)	result address
				2801+*			INSTRUCTION UNDER TEST ROUTINE
00002D84				2802+X82	DS	OF	
00002D84	E710 8F40 0006		00001140	2803+	VL	V1, V1FUDGE	pollute V1
00002D8A	E320 5050 0004		00002DB8	2804+	LG	R2, RE82+16	get R2 source
00002D90	E612 0098 905A			2805+	VCVDG	V1, R2, 137, 9	test instruction
00002D96	E710 8F08 000E		00001108	2806+	VST	V1, V10UTPUT	save
00002D9C	B98D 0020			2807+	EPSW	R2, R0	exptract psw
00002DA0	5020 8EE4		000010E4	2808+	ST	R2, CCPSW	to save CC
00002DA4	07FB			2809+	BR	R11	return
00002DA8				2810+RE82	DC	OF	
00002DA8				2811+	DROP	R5	
00002DA8	00000000 00000000			2812	DC	XL16' 000000000000000000000000000000001C'	V1 result
00002DB0	00000000 0000001C						
00002DB8	00000000 00000001			2813	DC	FD' 1'	R2 source
				2814			
				2815	VRR_K	VCVDG, 137, 9, 3	UINT_MAX
00002DC0				2816+	DS	OFD	
00002DC0		00002DC0		2817+	USING	*, R5	base for test data and test routine
00002DC0	00002DDC			2818+T83	DC	A(X83)	address of test routine
00002DC4	0053			2819+	DC	H' 83'	test number
00002DC6	00			2820+	DC	XL1' 00'	
00002DC7	89			2821+	DC	HL1' 137'	i3
00002DC8	09			2822+	DC	HL1' 9'	m4
00002DC9	03			2823+	DC	HL1' 3'	cc
00002DCA	0E			2824+	DC	HL1' 14'	cc failed mask
00002DCB	E5C3E5C4 C7404040			2825+	DC	CL8' VCVDG'	instruction name
00002DD4	00000010			2826+	DC	A(16)	result length
00002DD8	00002E00			2827+REA83	DC	A(RE83)	result address
				2828+*			INSTRUCTION UNDER TEST ROUTINE
00002DDC				2829+X83	DS	OF	
00002DDC	E710 8F40 0006		00001140	2830+	VL	V1, V1FUDGE	pollute V1
00002DE2	E320 5050 0004		00002E10	2831+	LG	R2, RE83+16	get R2 source
00002DE8	E612 0098 905A			2832+	VCVDG	V1, R2, 137, 9	test instruction
00002DEE	E710 8F08 000E		00001108	2833+	VST	V1, V10UTPUT	save
00002DF4	B98D 0020			2834+	EPSW	R2, R0	exptract psw
00002DF8	5020 8EE4		000010E4	2835+	ST	R2, CCPSW	to save CC
00002DFC	07FB			2836+	BR	R11	return
00002E00				2837+RE83	DC	OF	
00002E00				2838+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002E00	00000000 00000000			2839	DC	XL16' 000000000000000000000000709551615C'	V1 source
00002E08	00000070 9551615C						
00002E10	FFFFFFFF FFFFFFFF			2840	DC	FD' - 1'	R2 source
				2841			
				2842	VRR_K	VCVDG, 137, 9, 3	INT_MAX
00002E18				2843+	DS	OFD	
00002E18		00002E18		2844+	USING	*, R5	base for test data and test routine
00002E18	00002E34			2845+T84	DC	A(X84)	address of test routine
00002E1C	0054			2846+	DC	H' 84'	test number
00002E1E	00			2847+	DC	XL1' 00'	
00002E1F	89			2848+	DC	HL1' 137'	i3
00002E20	09			2849+	DC	HL1' 9'	m4
00002E21	03			2850+	DC	HL1' 3'	cc
00002E22	0E			2851+	DC	HL1' 14'	cc failed mask
00002E23	E5C3E5C4 C7404040			2852+	DC	CL8' VCVDG'	instruction name
00002E2C	00000010			2853+	DC	A(16)	result length
00002E30	00002E58			2854+REA84	DC	A(RE84)	result address
				2855+*			INSTRUCTION UNDER TEST ROUTINE
00002E34				2856+X84	DS	OF	
00002E34	E710 8F40 0006		00001140	2857+	VL	V1, V1FUDGE	pollute V1
00002E3A	E320 5050 0004		00002E68	2858+	LG	R2, RE84+16	get R2 source
00002E40	E612 0098 905A			2859+	VCVDG	V1, R2, 137, 9	test instruction
00002E46	E710 8F08 000E		00001108	2860+	VST	V1, V10UTPUT	save
00002E4C	B98D 0020			2861+	EPSW	R2, R0	exptract psw
00002E50	5020 8EE4		000010E4	2862+	ST	R2, CCPSW	to save CC
00002E54	07FB			2863+	BR	R11	return
00002E58				2864+RE84	DC	OF	
00002E58				2865+	DROP	R5	
00002E58	00000000 00000000			2866	DC	XL16' 000000000000000000000000147483647C'	V1 result
00002E60	00000014 7483647C						
00002E68	00000000 7FFFFFFF			2867	DC	FD' 2147483647'	R2 source
				2868			
				2869	VRR_K	VCVDG, 137, 9, 3	INT_MIN
00002E70				2870+	DS	OFD	
00002E70		00002E70		2871+	USING	*, R5	base for test data and test routine
00002E70	00002E8C			2872+T85	DC	A(X85)	address of test routine
00002E74	0055			2873+	DC	H' 85'	test number
00002E76	00			2874+	DC	XL1' 00'	
00002E77	89			2875+	DC	HL1' 137'	i3
00002E78	09			2876+	DC	HL1' 9'	m4
00002E79	03			2877+	DC	HL1' 3'	cc
00002E7A	0E			2878+	DC	HL1' 14'	cc failed mask
00002E7B	E5C3E5C4 C7404040			2879+	DC	CL8' VCVDG'	instruction name
00002E84	00000010			2880+	DC	A(16)	result length
00002E88	00002EB0			2881+REA85	DC	A(RE85)	result address
				2882+*			INSTRUCTION UNDER TEST ROUTINE
00002E8C				2883+X85	DS	OF	
00002E8C	E710 8F40 0006		00001140	2884+	VL	V1, V1FUDGE	pollute V1
00002E92	E320 5050 0004		00002EC0	2885+	LG	R2, RE85+16	get R2 source
00002E98	E612 0098 905A			2886+	VCVDG	V1, R2, 137, 9	test instruction
00002E9E	E710 8F08 000E		00001108	2887+	VST	V1, V10UTPUT	save
00002EA4	B98D 0020			2888+	EPSW	R2, R0	exptract psw
00002EA8	5020 8EE4		000010E4	2889+	ST	R2, CCPSW	to save CC
00002EAC	07FB			2890+	BR	R11	return
00002EB0				2891+RE85	DC	OF	
00002EB0				2892+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002EB0	00000000 00000000			2893	DC	XL16' 000000000000000000000000562067968C'	V1 result
00002EB8	00000056 2067968C						
00002EC0	FFFFFFFF 80000000			2894	DC	FD' - 2147483648'	
				2895			
				2896	VRR_K	VCVDG, 137, 9, 3	LONG_MAX
00002EC8				2897+	DS	OFD	
00002EC8		00002EC8		2898+	USING	*, R5	base for test data and test routine
00002EC8	00002EE4			2899+T86	DC	A(X86)	address of test routine
00002ECC	0056			2900+	DC	H' 86'	test number
00002ECE	00			2901+	DC	XL1' 00'	
00002ECF	89			2902+	DC	HL1' 137'	i3
00002ED0	09			2903+	DC	HL1' 9'	m4
00002ED1	03			2904+	DC	HL1' 3'	cc
00002ED2	0E			2905+	DC	HL1' 14'	cc failed mask
00002ED3	E5C3E5C4 C7404040			2906+	DC	CL8' VCVDG'	instruction name
00002EDC	00000010			2907+	DC	A(16)	result length
00002EE0	00002F08			2908+REA86	DC	A(RE86)	result address
				2909+*			INSTRUCTION UNDER TEST ROUTINE
00002EE4				2910+X86	DS	OF	
00002EE4	E710 8F40 0006		00001140	2911+	VL	V1, V1FUDGE	pollute V1
00002EEA	E320 5050 0004		00002F18	2912+	LG	R2, RE86+16	get R2 source
00002EF0	E612 0098 905A			2913+	VCVDG	V1, R2, 137, 9	test instruction
00002EF6	E710 8F08 000E		00001108	2914+	VST	V1, V10UTPUT	save
00002EFC	B98D 0020			2915+	EPSW	R2, R0	exptract psw
00002F00	5020 8EE4		000010E4	2916+	ST	R2, CCPSW	to save CC
00002F04	07FB			2917+	BR	R11	return
00002F08				2918+RE86	DC	OF	
00002F08				2919+	DROP	R5	
00002F08	00000000 00000000			2920	DC	XL16' 000000000000000000000000854775807C'	V1 source
00002F10	00000085 4775807C						
00002F18	7FFFFFFFF FFFFFFFF			2921	DC	XL08' 7FFFFFFFFFFFFFFFFF'	R1 result
				2922			
				2923	VRR_K	VCVDG, 137, 9, 3	LONG_MIN
00002F20				2924+	DS	OFD	
00002F20		00002F20		2925+	USING	*, R5	base for test data and test routine
00002F20	00002F3C			2926+T87	DC	A(X87)	address of test routine
00002F24	0057			2927+	DC	H' 87'	test number
00002F26	00			2928+	DC	XL1' 00'	
00002F27	89			2929+	DC	HL1' 137'	i3
00002F28	09			2930+	DC	HL1' 9'	m4
00002F29	03			2931+	DC	HL1' 3'	cc
00002F2A	0E			2932+	DC	HL1' 14'	cc failed mask
00002F2B	E5C3E5C4 C7404040			2933+	DC	CL8' VCVDG'	instruction name
00002F34	00000010			2934+	DC	A(16)	result length
00002F38	00002F60			2935+REA87	DC	A(RE87)	result address
				2936+*			INSTRUCTION UNDER TEST ROUTINE
00002F3C				2937+X87	DS	OF	
00002F3C	E710 8F40 0006		00001140	2938+	VL	V1, V1FUDGE	pollute V1
00002F42	E320 5050 0004		00002F70	2939+	LG	R2, RE87+16	get R2 source
00002F48	E612 0098 905A			2940+	VCVDG	V1, R2, 137, 9	test instruction
00002F4E	E710 8F08 000E		00001108	2941+	VST	V1, V10UTPUT	save
00002F54	B98D 0020			2942+	EPSW	R2, R0	exptract psw
00002F58	5020 8EE4		000010E4	2943+	ST	R2, CCPSW	to save CC
00002F5C	07FB			2944+	BR	R11	return
00002F60				2945+RE87	DC	OF	
00002F60				2946+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002F60	00000000 00000000			2947	DC	XL16' 0000000000000000000000000854775808C'	V1 source
00002F68	00000085 4775808C						
00002F70	80000000 00000000			2948	DC	XL08' 800000000000000000'	R1 result
				2949			
				2950	VRR_K	VCVDG, 137, 9, 3	ULONG_MAX
00002F78				2951+	DS	OFD	
00002F78		00002F78		2952+	USING	*, R5	base for test data and test routine
00002F78	00002F94			2953+T88	DC	A(X88)	address of test routine
00002F7C	0058			2954+	DC	H' 88'	test number
00002F7E	00			2955+	DC	XL1' 00'	
00002F7F	89			2956+	DC	HL1' 137'	i3
00002F80	09			2957+	DC	HL1' 9'	m4
00002F81	03			2958+	DC	HL1' 3'	cc
00002F82	0E			2959+	DC	HL1' 14'	cc failed mask
00002F83	E5C3E5C4 C7404040			2960+	DC	CL8' VCVDG'	instruction name
00002F8C	00000010			2961+	DC	A(16)	result length
00002F90	00002FB8			2962+REA88	DC	A(RE88)	result address
				2963+*			INSTRUCTION UNDER TEST ROUTINE
00002F94				2964+X88	DS	OF	
00002F94	E710 8F40 0006		00001140	2965+	VL	V1, V1FUDGE	pollute V1
00002F9A	E320 5050 0004		00002FC8	2966+	LG	R2, RE88+16	get R2 source
00002FA0	E612 0098 905A			2967+	VCVDG	V1, R2, 137, 9	test instruction
00002FA6	E710 8F08 000E		00001108	2968+	VST	V1, V10UTPUT	save
00002FAC	B98D 0020			2969+	EPSW	R2, R0	exptract psw
00002FB0	5020 8EE4		000010E4	2970+	ST	R2, CCPSW	to save CC
00002FB4	07FB			2971+	BR	R11	return
00002FB8				2972+RE88	DC	OF	
00002FB8				2973+	DROP	R5	
00002FB8	00000000 00000000			2974	DC	XL16' 000000000000000000000000709551615C'	V1 source
00002FC0	00000070 9551615C						
00002FC8	FFFFFFFF FFFFFFFF			2975	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				2976			
				2977 *			
				2978 * VCVDG		m4= 11 (LB=1, P1=1 , CS=1)	
				2979 *		i3= 159 (IOM=1, RDC=31)	
				2980			
00002FD0				2981	VRR_K	VCVDG, 159, 11, 0	
00002FD0		00002FD0		2982+	DS	OFD	
00002FD0	00002FEC			2983+	USING	*, R5	base for test data and test routine
00002FD4	0059			2984+T89	DC	A(X89)	address of test routine
00002FD6	00			2985+	DC	H' 89'	test number
00002FD7	9F			2986+	DC	XL1' 00'	
00002FD8	0B			2987+	DC	HL1' 159'	i3
00002FD9	00			2988+	DC	HL1' 11'	m4
00002FDA	07			2989+	DC	HL1' 0'	cc
00002FDB	E5C3E5C4 C7404040			2990+	DC	HL1' 7'	cc failed mask
00002FE4	00000010			2991+	DC	CL8' VCVDG'	instruction name
00002FE8	00003010			2992+	DC	A(16)	result length
				2993+REA89	DC	A(RE89)	result address
				2994+*			INSTRUCTION UNDER TEST ROUTINE
00002FEC				2995+X89	DS	OF	
00002FEC	E710 8F40 0006		00001140	2996+	VL	V1, V1FUDGE	pollute V1
00002FF2	E320 5050 0004		00003020	2997+	LG	R2, RE89+16	get R2 source
00002FF8	E612 00B9 F05A			2998+	VCVDG	V1, R2, 159, 11	test instruction
00002FFE	E710 8F08 000E		00001108	2999+	VST	V1, V10UTPUT	save
00003004	B98D 0020			3000+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003008	5020 8EE4		000010E4	3001+	ST	R2, CCPSW	to save CC
0000300C	07FB			3002+	BR	R11	return
00003010				3003+RE89	DC	0F	
00003010				3004+	DROP	R5	
00003010	00000000 00000000			3005	DC	XL16' 000000000000000000000000000000F'	V1 result
00003018	00000000 0000000F						
00003020	00000000 00000000			3006	DC	FD' 0'	R2 source
				3007			
				3008	VRR_K	VCVDG, 159, 11, 0	
00003028				3009+	DS	0FD	
00003028		00003028		3010+	USING	*, R5	base for test data and test routine
00003028	00003044			3011+T90	DC	A(X90)	address of test routine
0000302C	005A			3012+	DC	H' 90'	test number
0000302E	00			3013+	DC	XL1' 00'	
0000302F	9F			3014+	DC	HL1' 159'	i3
00003030	0B			3015+	DC	HL1' 11'	m4
00003031	00			3016+	DC	HL1' 0'	cc
00003032	07			3017+	DC	HL1' 7'	cc failed mask
00003033	E5C3E5C4 C7404040			3018+	DC	CL8' VCVDG'	instruction name
0000303C	00000010			3019+	DC	A(16)	result length
00003040	00003068			3020+REA90	DC	A(RE90)	result address
				3021+*			INSTRUCTION UNDER TEST ROUTINE
00003044				3022+X90	DS	0F	
00003044	E710 8F40 0006		00001140	3023+	VL	V1, V1FUDGE	pollute V1
0000304A	E320 5050 0004		00003078	3024+	LG	R2, RE90+16	get R2 source
00003050	E612 00B9 F05A			3025+	VCVDG	V1, R2, 159, 11	test instruction
00003056	E710 8F08 000E		00001108	3026+	VST	V1, V10UTPUT	save
0000305C	B98D 0020			3027+	EPSW	R2, R0	exptract psw
00003060	5020 8EE4		000010E4	3028+	ST	R2, CCPSW	to save CC
00003064	07FB			3029+	BR	R11	return
00003068				3030+RE90	DC	0F	
00003068				3031+	DROP	R5	
00003068	00000000 00000000			3032	DC	XL16' 000000000000000000000000000001F'	V1 result
00003070	00000000 0000001F						
00003078	00000000 00000001			3033	DC	FD' 1'	R2 source
				3034			
				3035	VRR_K	VCVDG, 159, 11, 0	UINT_MAX
00003080				3036+	DS	0FD	
00003080		00003080		3037+	USING	*, R5	base for test data and test routine
00003080	0000309C			3038+T91	DC	A(X91)	address of test routine
00003084	005B			3039+	DC	H' 91'	test number
00003086	00			3040+	DC	XL1' 00'	
00003087	9F			3041+	DC	HL1' 159'	i3
00003088	0B			3042+	DC	HL1' 11'	m4
00003089	00			3043+	DC	HL1' 0'	cc
0000308A	07			3044+	DC	HL1' 7'	cc failed mask
0000308B	E5C3E5C4 C7404040			3045+	DC	CL8' VCVDG'	instruction name
00003094	00000010			3046+	DC	A(16)	result length
00003098	000030C0			3047+REA91	DC	A(RE91)	result address
				3048+*			INSTRUCTION UNDER TEST ROUTINE
0000309C				3049+X91	DS	0F	
0000309C	E710 8F40 0006		00001140	3050+	VL	V1, V1FUDGE	pollute V1
000030A2	E320 5050 0004		000030D0	3051+	LG	R2, RE91+16	get R2 source
000030A8	E612 00B9 F05A			3052+	VCVDG	V1, R2, 159, 11	test instruction
000030AE	E710 8F08 000E		00001108	3053+	VST	V1, V10UTPUT	save
000030B4	B98D 0020			3054+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000030B8	5020 8EE4		000010E4	3055+	ST	R2, CCPSW	to save CC
000030BC	07FB			3056+	BR	R11	return
000030C0				3057+RE91	DC	0F	
000030C0				3058+	DROP	R5	
000030C0	00000000 00018446			3059	DC	XL16' 00000000000018446744073709551615F'	V1 source
000030C8	74407370 9551615F						
000030D0	FFFFFFFF FFFFFFFF			3060	DC	FD' - 1'	R2 source
				3061			
				3062	VRR_K	VCVDG, 159, 11, 0	INT_MAX
000030D8				3063+	DS	0FD	
000030D8		000030D8		3064+	USING	*, R5	base for test data and test routine
000030D8	000030F4			3065+T92	DC	A(X92)	address of test routine
000030DC	005C			3066+	DC	H' 92'	test number
000030DE	00			3067+	DC	XL1' 00'	
000030DF	9F			3068+	DC	HL1' 159'	i3
000030E0	0B			3069+	DC	HL1' 11'	m4
000030E1	00			3070+	DC	HL1' 0'	cc
000030E2	07			3071+	DC	HL1' 7'	cc failed mask
000030E3	E5C3E5C4 C7404040			3072+	DC	CL8' VCVDG'	instruction name
000030EC	00000010			3073+	DC	A(16)	result length
000030F0	00003118			3074+REA92	DC	A(RE92)	result address
				3075+*			INSTRUCTION UNDER TEST ROUTINE
000030F4				3076+X92	DS	0F	
000030F4	E710 8F40 0006		00001140	3077+	VL	V1, V1FUDGE	pollute V1
000030FA	E320 5050 0004		00003128	3078+	LG	R2, RE92+16	get R2 source
00003100	E612 00B9 F05A			3079+	VCVDG	V1, R2, 159, 11	test instruction
00003106	E710 8F08 000E		00001108	3080+	VST	V1, V10UTPUT	save
0000310C	B98D 0020			3081+	EPSW	R2, R0	exptract psw
00003110	5020 8EE4		000010E4	3082+	ST	R2, CCPSW	to save CC
00003114	07FB			3083+	BR	R11	return
00003118				3084+RE92	DC	0F	
00003118				3085+	DROP	R5	
00003118	00000000 00000000			3086	DC	XL16' 00000000000000000000002147483647F'	V1 result
00003120	00000214 7483647F						
00003128	00000000 7FFFFFFF			3087	DC	FD' 2147483647'	R2 source
				3088			
				3089	VRR_K	VCVDG, 159, 11, 0	INT_MIN
00003130				3090+	DS	0FD	
00003130		00003130		3091+	USING	*, R5	base for test data and test routine
00003130	0000314C			3092+T93	DC	A(X93)	address of test routine
00003134	005D			3093+	DC	H' 93'	test number
00003136	00			3094+	DC	XL1' 00'	
00003137	9F			3095+	DC	HL1' 159'	i3
00003138	0B			3096+	DC	HL1' 11'	m4
00003139	00			3097+	DC	HL1' 0'	cc
0000313A	07			3098+	DC	HL1' 7'	cc failed mask
0000313B	E5C3E5C4 C7404040			3099+	DC	CL8' VCVDG'	instruction name
00003144	00000010			3100+	DC	A(16)	result length
00003148	00003170			3101+REA93	DC	A(RE93)	result address
				3102+*			INSTRUCTION UNDER TEST ROUTINE
0000314C				3103+X93	DS	0F	
0000314C	E710 8F40 0006		00001140	3104+	VL	V1, V1FUDGE	pollute V1
00003152	E320 5050 0004		00003180	3105+	LG	R2, RE93+16	get R2 source
00003158	E612 00B9 F05A			3106+	VCVDG	V1, R2, 159, 11	test instruction
0000315E	E710 8F08 000E		00001108	3107+	VST	V1, V10UTPUT	save
00003164	B98D 0020			3108+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003168	5020 8EE4		000010E4	3109+	ST	R2, CCPSW	to save CC
0000316C	07FB			3110+	BR	R11	return
00003170				3111+RE93	DC	0F	
00003170				3112+	DROP	R5	
00003170	00000000 00018446			3113	DC	XL16' 00000000000018446744071562067968F'	V1 result
00003178	74407156 2067968F						
00003180	FFFFFFFF 80000000			3114	DC	XL8' FFFFFFFF80000000'	R2 source
				3115 *	DC	FD' - 2147483648'	R2 source
				3116			
				3117	VRR_K	VCVDG, 159, 11, 0	LONG_MAX
00003188				3118+	DS	0FD	
00003188		00003188		3119+	USING	*, R5	base for test data and test routine
00003188	000031A4			3120+T94	DC	A(X94)	address of test routine
0000318C	005E			3121+	DC	H' 94'	test number
0000318E	00			3122+	DC	XL1' 00'	
0000318F	9F			3123+	DC	HL1' 159'	i3
00003190	0B			3124+	DC	HL1' 11'	m4
00003191	00			3125+	DC	HL1' 0'	cc
00003192	07			3126+	DC	HL1' 7'	cc failed mask
00003193	E5C3E5C4 C7404040			3127+	DC	CL8' VCVDG'	instruction name
0000319C	00000010			3128+	DC	A(16)	result length
000031A0	000031C8			3129+REA94	DC	A(RE94)	result address
				3130+*			INSTRUCTION UNDER TEST ROUTINE
000031A4				3131+X94	DS	0F	
000031A4	E710 8F40 0006		00001140	3132+	VL	V1, V1FUDGE	pollute V1
000031AA	E320 5050 0004		000031D8	3133+	LG	R2, RE94+16	get R2 source
000031B0	E612 00B9 F05A			3134+	VCVDG	V1, R2, 159, 11	test instruction
000031B6	E710 8F08 000E		00001108	3135+	VST	V1, V10UTPUT	save
000031BC	B98D 0020			3136+	EPSW	R2, R0	extract psw
000031C0	5020 8EE4		000010E4	3137+	ST	R2, CCPSW	to save CC
000031C4	07FB			3138+	BR	R11	return
000031C8				3139+RE94	DC	0F	
000031C8				3140+	DROP	R5	
000031C8	00000000 00009223			3141	DC	XL16' 00000000000009223372036854775807F'	V1 source
000031D0	37203685 4775807F						
000031D8	7FFFFFFFF FFFFFFFF			3142	DC	XL08' 7FFFFFFFFFFFFFFFFF'	R1 result
				3143			
				3144	VRR_K	VCVDG, 159, 11, 0	LONG_MIN
000031E0				3145+	DS	0FD	
000031E0		000031E0		3146+	USING	*, R5	base for test data and test routine
000031E0	000031FC			3147+T95	DC	A(X95)	address of test routine
000031E4	005F			3148+	DC	H' 95'	test number
000031E6	00			3149+	DC	XL1' 00'	
000031E7	9F			3150+	DC	HL1' 159'	i3
000031E8	0B			3151+	DC	HL1' 11'	m4
000031E9	00			3152+	DC	HL1' 0'	cc
000031EA	07			3153+	DC	HL1' 7'	cc failed mask
000031EB	E5C3E5C4 C7404040			3154+	DC	CL8' VCVDG'	instruction name
000031F4	00000010			3155+	DC	A(16)	result length
000031F8	00003220			3156+REA95	DC	A(RE95)	result address
				3157+*			INSTRUCTION UNDER TEST ROUTINE
000031FC				3158+X95	DS	0F	
000031FC	E710 8F40 0006		00001140	3159+	VL	V1, V1FUDGE	pollute V1
00003202	E320 5050 0004		00003230	3160+	LG	R2, RE95+16	get R2 source
00003208	E612 00B9 F05A			3161+	VCVDG	V1, R2, 159, 11	test instruction
0000320E	E710 8F08 000E		00001108	3162+	VST	V1, V10UTPUT	save

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003214	B98D 0020			3163+	EPSW	R2, R0	extract psw
00003218	5020 8EE4		000010E4	3164+	ST	R2, CCPSW	to save CC
0000321C	07FB			3165+	BR	R11	return
00003220				3166+RE95	DC	0F	
00003220				3167+	DROP	R5	
00003220	00000000 00009223			3168	DC	XL16' 0000000000009223372036854775808F'	V1 source
00003228	37203685 4775808F						
00003230	80000000 00000000			3169	DC	XL08' 8000000000000000'	R1 result
				3170			
				3171	VRR_K	VCVDG, 159, 11, 0	ULONG_MAX
00003238				3172+	DS	0FD	
00003238		00003238		3173+	USING	*, R5	base for test data and test routine
00003238	00003254			3174+T96	DC	A(X96)	address of test routine
0000323C	0060			3175+	DC	H' 96'	test number
0000323E	00			3176+	DC	XL1' 00'	
0000323F	9F			3177+	DC	HL1' 159'	i3
00003240	0B			3178+	DC	HL1' 11'	m4
00003241	00			3179+	DC	HL1' 0'	cc
00003242	07			3180+	DC	HL1' 7'	cc failed mask
00003243	E5C3E5C4 C7404040			3181+	DC	CL8' VCVDG'	instruction name
0000324C	00000010			3182+	DC	A(16)	result length
00003250	00003278			3183+REA96	DC	A(RE96)	result address
				3184+*			INSTRUCTION UNDER TEST ROUTINE
00003254				3185+X96	DS	0F	
00003254	E710 8F40 0006		00001140	3186+	VL	V1, V1FUDGE	pollute V1
0000325A	E320 5050 0004		00003288	3187+	LG	R2, RE96+16	get R2 source
00003260	E612 00B9 F05A			3188+	VCVDG	V1, R2, 159, 11	test instruction
00003266	E710 8F08 000E		00001108	3189+	VST	V1, V10UTPUT	save
0000326C	B98D 0020			3190+	EPSW	R2, R0	extract psw
00003270	5020 8EE4		000010E4	3191+	ST	R2, CCPSW	to save CC
00003274	07FB			3192+	BR	R11	return
00003278				3193+RE96	DC	0F	
00003278				3194+	DROP	R5	
00003278	00000000 00018446			3195	DC	XL16' 00000000000018446744073709551615F'	V1 source
00003280	74407370 9551615F						
00003288	FFFFFFFF FFFFFFFF			3196	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				3197			
				3198 * VCVDG		m4= 11 (LB=1, P1=1 , CS=1)	
				3199 *		i3= 137 (IOM=1, RDC= 9)	
				3200			
				3201	VRR_K	VCVDG, 137, 11, 0	
00003290				3202+	DS	0FD	
00003290		00003290		3203+	USING	*, R5	base for test data and test routine
00003290	000032AC			3204+T97	DC	A(X97)	address of test routine
00003294	0061			3205+	DC	H' 97'	test number
00003296	00			3206+	DC	XL1' 00'	
00003297	89			3207+	DC	HL1' 137'	i3
00003298	0B			3208+	DC	HL1' 11'	m4
00003299	00			3209+	DC	HL1' 0'	cc
0000329A	07			3210+	DC	HL1' 7'	cc failed mask
0000329B	E5C3E5C4 C7404040			3211+	DC	CL8' VCVDG'	instruction name
000032A4	00000010			3212+	DC	A(16)	result length
000032A8	000032D0			3213+REA97	DC	A(RE97)	result address
				3214+*			INSTRUCTION UNDER TEST ROUTINE
000032AC				3215+X97	DS	0F	
000032AC	E710 8F40 0006		00001140	3216+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000032B2	E320 5050 0004		000032E0	3217+	1G	R2, RE97+16	get R2 source
000032B8	E612 00B8 905A			3218+	VCVDG	V1, R2, 137, 11	test instruction
000032BE	E710 8F08 000E		00001108	3219+	VST	V1, V10UTPUT	save
000032C4	B98D 0020			3220+	EPSW	R2, R0	exptract psw
000032C8	5020 8EE4		000010E4	3221+	ST	R2, CCPSW	to save CC
000032CC	07FB			3222+	BR	R11	return
000032D0				3223+RE97	DC	0F	
000032D0				3224+	DROP	R5	
000032D0	00000000 00000000			3225	DC	XL16' 00000000000000000000000000000000F'	V1 result
000032D8	00000000 0000000F						
000032E0	00000000 00000000			3226	DC	FD' 0'	R2 source
				3227			
				3228	VRR_K	VCVDG, 137, 11, 0	
000032E8				3229+	DS	0FD	
000032E8		000032E8		3230+	USING	*, R5	base for test data and test routine
000032E8	00003304			3231+T98	DC	A(X98)	address of test routine
000032EC	0062			3232+	DC	H' 98'	test number
000032EE	00			3233+	DC	XL1' 00'	
000032EF	89			3234+	DC	HL1' 137'	i3
000032F0	0B			3235+	DC	HL1' 11'	m4
000032F1	00			3236+	DC	HL1' 0'	cc
000032F2	07			3237+	DC	HL1' 7'	cc failed mask
000032F3	E5C3E5C4 C7404040			3238+	DC	CL8' VCVDG'	instruction name
000032FC	00000010			3239+	DC	A(16)	result length
00003300	00003328			3240+REA98	DC	A(RE98)	result address
				3241+*			INSTRUCTION UNDER TEST ROUTINE
00003304				3242+X98	DS	0F	
00003304	E710 8F40 0006		00001140	3243+	VL	V1, V1FUDGE	pollute V1
0000330A	E320 5050 0004		00003338	3244+	1G	R2, RE98+16	get R2 source
00003310	E612 00B8 905A			3245+	VCVDG	V1, R2, 137, 11	test instruction
00003316	E710 8F08 000E		00001108	3246+	VST	V1, V10UTPUT	save
0000331C	B98D 0020			3247+	EPSW	R2, R0	exptract psw
00003320	5020 8EE4		000010E4	3248+	ST	R2, CCPSW	to save CC
00003324	07FB			3249+	BR	R11	return
00003328				3250+RE98	DC	0F	
00003328				3251+	DROP	R5	
00003328	00000000 00000000			3252	DC	XL16' 000000000000000000000000000000001F'	V1 result
00003330	00000000 0000001F						
00003338	00000000 00000001			3253	DC	FD' 1'	R2 source
				3254			
				3255	VRR_K	VCVDG, 137, 11, 3	UINT_MAX
00003340				3256+	DS	0FD	
00003340		00003340		3257+	USING	*, R5	base for test data and test routine
00003340	0000335C			3258+T99	DC	A(X99)	address of test routine
00003344	0063			3259+	DC	H' 99'	test number
00003346	00			3260+	DC	XL1' 00'	
00003347	89			3261+	DC	HL1' 137'	i3
00003348	0B			3262+	DC	HL1' 11'	m4
00003349	03			3263+	DC	HL1' 3'	cc
0000334A	0E			3264+	DC	HL1' 14'	cc failed mask
0000334B	E5C3E5C4 C7404040			3265+	DC	CL8' VCVDG'	instruction name
00003354	00000010			3266+	DC	A(16)	result length
00003358	00003380			3267+REA99	DC	A(RE99)	result address
				3268+*			INSTRUCTION UNDER TEST ROUTINE
0000335C				3269+X99	DS	0F	
0000335C	E710 8F40 0006		00001140	3270+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003362	E320 5050 0004		00003390	3271+	1G	R2, RE99+16	get R2 source
00003368	E612 00B8 905A			3272+	VCVDG	V1, R2, 137, 11	test instruction
0000336E	E710 8F08 000E		00001108	3273+	VST	V1, V10UTPUT	save
00003374	B98D 0020			3274+	EPSW	R2, R0	exptract psw
00003378	5020 8EE4		000010E4	3275+	ST	R2, CCPSW	to save CC
0000337C	07FB			3276+	BR	R11	return
00003380				3277+RE99	DC	0F	
00003380				3278+	DROP	R5	
00003380	00000000 00000000			3279	DC	XL16' 000000000000000000000000709551615F'	V1 source
00003388	00000070 9551615F						
00003390	FFFFFFFF FFFFFFFF			3280	DC	FD' - 1'	R2 source
				3281			
				3282	VRR_K	VCVDG, 137, 11, 3	INT_MAX
00003398				3283+	DS	0FD	
00003398		00003398		3284+	USING	*, R5	base for test data and test routine
00003398	000033B4			3285+T100	DC	A(X100)	address of test routine
0000339C	0064			3286+	DC	H' 100'	test number
0000339E	00			3287+	DC	XL1' 00'	
0000339F	89			3288+	DC	HL1' 137'	i3
000033A0	0B			3289+	DC	HL1' 11'	m4
000033A1	03			3290+	DC	HL1' 3'	cc
000033A2	0E			3291+	DC	HL1' 14'	cc failed mask
000033A3	E5C3E5C4 C7404040			3292+	DC	CL8' VCVDG'	instruction name
000033AC	00000010			3293+	DC	A(16)	result length
000033B0	000033D8			3294+REA100	DC	A(RE100)	result address
				3295+*			INSTRUCTION UNDER TEST ROUTINE
000033B4				3296+X100	DS	0F	
000033B4	E710 8F40 0006		00001140	3297+	VL	V1, V1FUDGE	pollute V1
000033BA	E320 5050 0004		000033E8	3298+	1G	R2, RE100+16	get R2 source
000033C0	E612 00B8 905A			3299+	VCVDG	V1, R2, 137, 11	test instruction
000033C6	E710 8F08 000E		00001108	3300+	VST	V1, V10UTPUT	save
000033CC	B98D 0020			3301+	EPSW	R2, R0	exptract psw
000033D0	5020 8EE4		000010E4	3302+	ST	R2, CCPSW	to save CC
000033D4	07FB			3303+	BR	R11	return
000033D8				3304+RE100	DC	0F	
000033D8				3305+	DROP	R5	
000033D8	00000000 00000000			3306	DC	XL16' 000000000000000000000000147483647F'	V1 result
000033E0	00000014 7483647F						
000033E8	00000000 7FFFFFFF			3307	DC	FD' 2147483647'	R2 source
				3308			
				3309	VRR_K	VCVDG, 137, 11, 3	INT_MIN
000033F0				3310+	DS	0FD	
000033F0		000033F0		3311+	USING	*, R5	base for test data and test routine
000033F0	0000340C			3312+T101	DC	A(X101)	address of test routine
000033F4	0065			3313+	DC	H' 101'	test number
000033F6	00			3314+	DC	XL1' 00'	
000033F7	89			3315+	DC	HL1' 137'	i3
000033F8	0B			3316+	DC	HL1' 11'	m4
000033F9	03			3317+	DC	HL1' 3'	cc
000033FA	0E			3318+	DC	HL1' 14'	cc failed mask
000033FB	E5C3E5C4 C7404040			3319+	DC	CL8' VCVDG'	instruction name
00003404	00000010			3320+	DC	A(16)	result length
00003408	00003430			3321+REA101	DC	A(RE101)	result address
				3322+*			INSTRUCTION UNDER TEST ROUTINE
0000340C				3323+X101	DS	0F	
0000340C	E710 8F40 0006		00001140	3324+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003412	E320 5050 0004		00003440	3325+	1G	R2, RE101+16	get R2 source
00003418	E612 00B8 905A			3326+	VCVDG	V1, R2, 137, 11	test instruction
0000341E	E710 8F08 000E		00001108	3327+	VST	V1, V10UTPUT	save
00003424	B98D 0020			3328+	EPSW	R2, R0	exptract psw
00003428	5020 8EE4		000010E4	3329+	ST	R2, CCPSW	to save CC
0000342C	07FB			3330+	BR	R11	return
00003430				3331+RE101	DC	0F	
00003430				3332+	DROP	R5	
00003430	00000000 00000000			3333	DC	XL16' 000000000000000000000000562067968F'	V1 result
00003438	00000056 2067968F						
00003440	FFFFFFFF 80000000			3334	DC	XL8' FFFFFFFF80000000'	R2 source
				3335 *	DC	FD' - 2147483648'	R2 sourc
				3336			
				3337	VRR_K	VCVDG, 137, 11, 3	LONG_MAX
00003448				3338+	DS	0FD	
00003448		00003448		3339+	USING	*, R5	base for test data and test routine
00003448	00003464			3340+T102	DC	A(X102)	address of test routine
0000344C	0066			3341+	DC	H' 102'	test number
0000344E	00			3342+	DC	XL1' 00'	
0000344F	89			3343+	DC	HL1' 137'	i3
00003450	0B			3344+	DC	HL1' 11'	m4
00003451	03			3345+	DC	HL1' 3'	cc
00003452	0E			3346+	DC	HL1' 14'	cc failed mask
00003453	E5C3E5C4 C7404040			3347+	DC	CL8' VCVDG'	instruction name
0000345C	00000010			3348+	DC	A(16)	result length
00003460	00003488			3349+REA102	DC	A(RE102)	result address
				3350+*			INSTRUCTION UNDER TEST ROUTINE
00003464				3351+X102	DS	0F	
00003464	E710 8F40 0006		00001140	3352+	VL	V1, V1FUDGE	pollute V1
0000346A	E320 5050 0004		00003498	3353+	1G	R2, RE102+16	get R2 source
00003470	E612 00B8 905A			3354+	VCVDG	V1, R2, 137, 11	test instruction
00003476	E710 8F08 000E		00001108	3355+	VST	V1, V10UTPUT	save
0000347C	B98D 0020			3356+	EPSW	R2, R0	exptract psw
00003480	5020 8EE4		000010E4	3357+	ST	R2, CCPSW	to save CC
00003484	07FB			3358+	BR	R11	return
00003488				3359+RE102	DC	0F	
00003488				3360+	DROP	R5	
00003488	00000000 00000000			3361	DC	XL16' 000000000000000000000000854775807F'	V1 source
00003490	00000085 4775807F						
00003498	7FFFFFFFF FFFFFFFF			3362	DC	XL08' 7FFFFFFFFFFFFFFF'	R1 result
				3363			
				3364	VRR_K	VCVDG, 137, 11, 3	LONG_MIN
000034A0				3365+	DS	0FD	
000034A0		000034A0		3366+	USING	*, R5	base for test data and test routine
000034A0	000034BC			3367+T103	DC	A(X103)	address of test routine
000034A4	0067			3368+	DC	H' 103'	test number
000034A6	00			3369+	DC	XL1' 00'	
000034A7	89			3370+	DC	HL1' 137'	i3
000034A8	0B			3371+	DC	HL1' 11'	m4
000034A9	03			3372+	DC	HL1' 3'	cc
000034AA	0E			3373+	DC	HL1' 14'	cc failed mask
000034AB	E5C3E5C4 C7404040			3374+	DC	CL8' VCVDG'	instruction name
000034B4	00000010			3375+	DC	A(16)	result length
000034B8	000034E0			3376+REA103	DC	A(RE103)	result address
				3377+*			INSTRUCTION UNDER TEST ROUTINE
000034BC				3378+X103	DS	0F	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000034BC	E710 8F40 0006		00001140	3379+	VL	V1, V1FUDGE	pollute V1
000034C2	E320 5050 0004		000034F0	3380+	LG	R2, RE103+16	get R2 source
000034C8	E612 00B8 905A			3381+	VCVDG	V1, R2, 137, 11	test instruction
000034CE	E710 8F08 000E		00001108	3382+	VST	V1, V10UTPUT	save
000034D4	B98D 0020			3383+	EPSW	R2, R0	exptract psw
000034D8	5020 8EE4		000010E4	3384+	ST	R2, CCPSW	to save CC
000034DC	07FB			3385+	BR	R11	return
000034E0				3386+RE103	DC	0F	
000034E0				3387+	DROP	R5	
000034E0	00000000 00000000			3388	DC	XL16' 000000000000000000000000854775808F'	V1 source
000034E8	00000085 4775808F						
000034F0	80000000 00000000			3389	DC	XL08' 800000000000000000'	R1 result
				3390			
				3391	VRR_K	VCVDG, 137, 11, 3	ULONG_MAX
000034F8				3392+	DS	0FD	
000034F8		000034F8		3393+	USING	*, R5	base for test data and test routine
000034F8	00003514			3394+T104	DC	A(X104)	address of test routine
000034FC	0068			3395+	DC	H' 104'	test number
000034FE	00			3396+	DC	XL1' 00'	
000034FF	89			3397+	DC	HL1' 137'	i3
00003500	0B			3398+	DC	HL1' 11'	m4
00003501	03			3399+	DC	HL1' 3'	cc
00003502	0E			3400+	DC	HL1' 14'	cc failed mask
00003503	E5C3E5C4 C7404040			3401+	DC	CL8' VCVDG'	instruction name
0000350C	00000010			3402+	DC	A(16)	result length
00003510	00003538			3403+REA104	DC	A(RE104)	result address
				3404+*			INSTRUCTION UNDER TEST ROUTINE
00003514				3405+X104	DS	0F	
00003514	E710 8F40 0006		00001140	3406+	VL	V1, V1FUDGE	pollute V1
0000351A	E320 5050 0004		00003548	3407+	LG	R2, RE104+16	get R2 source
00003520	E612 00B8 905A			3408+	VCVDG	V1, R2, 137, 11	test instruction
00003526	E710 8F08 000E		00001108	3409+	VST	V1, V10UTPUT	save
0000352C	B98D 0020			3410+	EPSW	R2, R0	exptract psw
00003530	5020 8EE4		000010E4	3411+	ST	R2, CCPSW	to save CC
00003534	07FB			3412+	BR	R11	return
00003538				3413+RE104	DC	0F	
00003538				3414+	DROP	R5	
00003538	00000000 00000000			3415	DC	XL16' 000000000000000000000000709551615F'	V1 source
00003540	00000070 9551615F						
00003548	FFFFFFFF FFFFFFFF			3416	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				3417			
00003550	00000000			3418	DC	F' 0' END OF TABLE	
00003554	00000000			3419	DC	F' 0'	
				3420 *			
				3421 *	table of pointers to individual load test		
				3422 *			
00003558				3423 E6TESTS	DS	0F	
				3424	PTTABLE		
00003558				3425+TTABLE	DS	0F	
00003558	00001190			3426+	DC	A(T1)	address of test
0000355C	000011E8			3427+	DC	A(T2)	address of test
00003560	00001240			3428+	DC	A(T3)	address of test
00003564	00001298			3429+	DC	A(T4)	address of test
00003568	000012F0			3430+	DC	A(T5)	address of test
0000356C	00001348			3431+	DC	A(T6)	address of test
00003570	000013A0			3432+	DC	A(T7)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003574	000013F8			3433+	DC	A(T8)	address of test
00003578	00001450			3434+	DC	A(T9)	address of test
0000357C	000014A8			3435+	DC	A(T10)	address of test
00003580	00001500			3436+	DC	A(T11)	address of test
00003584	00001558			3437+	DC	A(T12)	address of test
00003588	000015B0			3438+	DC	A(T13)	address of test
0000358C	00001608			3439+	DC	A(T14)	address of test
00003590	00001660			3440+	DC	A(T15)	address of test
00003594	000016B8			3441+	DC	A(T16)	address of test
00003598	00001710			3442+	DC	A(T17)	address of test
0000359C	00001768			3443+	DC	A(T18)	address of test
000035A0	000017C0			3444+	DC	A(T19)	address of test
000035A4	00001818			3445+	DC	A(T20)	address of test
000035A8	00001870			3446+	DC	A(T21)	address of test
000035AC	000018C8			3447+	DC	A(T22)	address of test
000035B0	00001920			3448+	DC	A(T23)	address of test
000035B4	00001978			3449+	DC	A(T24)	address of test
000035B8	000019D0			3450+	DC	A(T25)	address of test
000035BC	00001A28			3451+	DC	A(T26)	address of test
000035C0	00001A80			3452+	DC	A(T27)	address of test
000035C4	00001AD8			3453+	DC	A(T28)	address of test
000035C8	00001B30			3454+	DC	A(T29)	address of test
000035CC	00001B88			3455+	DC	A(T30)	address of test
000035D0	00001BE0			3456+	DC	A(T31)	address of test
000035D4	00001C38			3457+	DC	A(T32)	address of test
000035D8	00001C90			3458+	DC	A(T33)	address of test
000035DC	00001CE8			3459+	DC	A(T34)	address of test
000035E0	00001D40			3460+	DC	A(T35)	address of test
000035E4	00001D98			3461+	DC	A(T36)	address of test
000035E8	00001DF0			3462+	DC	A(T37)	address of test
000035EC	00001E48			3463+	DC	A(T38)	address of test
000035F0	00001EA0			3464+	DC	A(T39)	address of test
000035F4	00001EF8			3465+	DC	A(T40)	address of test
000035F8	00001F50			3466+	DC	A(T41)	address of test
000035FC	00001FA8			3467+	DC	A(T42)	address of test
00003600	00002000			3468+	DC	A(T43)	address of test
00003604	00002058			3469+	DC	A(T44)	address of test
00003608	000020B0			3470+	DC	A(T45)	address of test
0000360C	00002108			3471+	DC	A(T46)	address of test
00003610	00002160			3472+	DC	A(T47)	address of test
00003614	000021B8			3473+	DC	A(T48)	address of test
00003618	00002210			3474+	DC	A(T49)	address of test
0000361C	00002268			3475+	DC	A(T50)	address of test
00003620	000022C0			3476+	DC	A(T51)	address of test
00003624	00002318			3477+	DC	A(T52)	address of test
00003628	00002370			3478+	DC	A(T53)	address of test
0000362C	000023C8			3479+	DC	A(T54)	address of test
00003630	00002420			3480+	DC	A(T55)	address of test
00003634	00002478			3481+	DC	A(T56)	address of test
00003638	000024D0			3482+	DC	A(T57)	address of test
0000363C	00002528			3483+	DC	A(T58)	address of test
00003640	00002580			3484+	DC	A(T59)	address of test
00003644	000025D8			3485+	DC	A(T60)	address of test
00003648	00002630			3486+	DC	A(T61)	address of test
0000364C	00002688			3487+	DC	A(T62)	address of test
00003650	000026E0			3488+	DC	A(T63)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003654	00002738			3489+	DC	A(T64)	address of test
00003658	00002790			3490+	DC	A(T65)	address of test
0000365C	000027E8			3491+	DC	A(T66)	address of test
00003660	00002840			3492+	DC	A(T67)	address of test
00003664	00002898			3493+	DC	A(T68)	address of test
00003668	000028F0			3494+	DC	A(T69)	address of test
0000366C	00002948			3495+	DC	A(T70)	address of test
00003670	000029A0			3496+	DC	A(T71)	address of test
00003674	000029F8			3497+	DC	A(T72)	address of test
00003678	00002A50			3498+	DC	A(T73)	address of test
0000367C	00002AA8			3499+	DC	A(T74)	address of test
00003680	00002B00			3500+	DC	A(T75)	address of test
00003684	00002B58			3501+	DC	A(T76)	address of test
00003688	00002BB0			3502+	DC	A(T77)	address of test
0000368C	00002C08			3503+	DC	A(T78)	address of test
00003690	00002C60			3504+	DC	A(T79)	address of test
00003694	00002CB8			3505+	DC	A(T80)	address of test
00003698	00002D10			3506+	DC	A(T81)	address of test
0000369C	00002D68			3507+	DC	A(T82)	address of test
000036A0	00002DC0			3508+	DC	A(T83)	address of test
000036A4	00002E18			3509+	DC	A(T84)	address of test
000036A8	00002E70			3510+	DC	A(T85)	address of test
000036AC	00002EC8			3511+	DC	A(T86)	address of test
000036B0	00002F20			3512+	DC	A(T87)	address of test
000036B4	00002F78			3513+	DC	A(T88)	address of test
000036B8	00002FD0			3514+	DC	A(T89)	address of test
000036BC	00003028			3515+	DC	A(T90)	address of test
000036C0	00003080			3516+	DC	A(T91)	address of test
000036C4	000030D8			3517+	DC	A(T92)	address of test
000036C8	00003130			3518+	DC	A(T93)	address of test
000036CC	00003188			3519+	DC	A(T94)	address of test
000036D0	000031E0			3520+	DC	A(T95)	address of test
000036D4	00003238			3521+	DC	A(T96)	address of test
000036D8	00003290			3522+	DC	A(T97)	address of test
000036DC	000032E8			3523+	DC	A(T98)	address of test
000036E0	00003340			3524+	DC	A(T99)	address of test
000036E4	00003398			3525+	DC	A(T100)	address of test
000036E8	000033F0			3526+	DC	A(T101)	address of test
000036EC	00003448			3527+	DC	A(T102)	address of test
000036F0	000034A0			3528+	DC	A(T103)	address of test
000036F4	000034F8			3529+	DC	A(T104)	address of test
				3530+*			
000036F8	00000000			3531+	DC	A(0)	END OF TABLE
000036FC	00000000			3532+	DC	A(0)	
				3533			
00003700	00000000			3534	DC	F' 0'	END OF TABLE
00003704	00000000			3535	DC	F' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				3537 *****	
				3538 * Register equates	
				3539 *****	
		00000000	00000001	3541 R0	EQU 0
		00000001	00000001	3542 R1	EQU 1
		00000002	00000001	3543 R2	EQU 2
		00000003	00000001	3544 R3	EQU 3
		00000004	00000001	3545 R4	EQU 4
		00000005	00000001	3546 R5	EQU 5
		00000006	00000001	3547 R6	EQU 6
		00000007	00000001	3548 R7	EQU 7
		00000008	00000001	3549 R8	EQU 8
		00000009	00000001	3550 R9	EQU 9
		0000000A	00000001	3551 R10	EQU 10
		0000000B	00000001	3552 R11	EQU 11
		0000000C	00000001	3553 R12	EQU 12
		0000000D	00000001	3554 R13	EQU 13
		0000000E	00000001	3555 R14	EQU 14
		0000000F	00000001	3556 R15	EQU 15
				3558 *****	
				3559 * Register equates	
				3560 *****	
		00000000	00000001	3562 V0	EQU 0
		00000001	00000001	3563 V1	EQU 1
		00000002	00000001	3564 V2	EQU 2
		00000003	00000001	3565 V3	EQU 3
		00000004	00000001	3566 V4	EQU 4
		00000005	00000001	3567 V5	EQU 5
		00000006	00000001	3568 V6	EQU 6
		00000007	00000001	3569 V7	EQU 7
		00000008	00000001	3570 V8	EQU 8
		00000009	00000001	3571 V9	EQU 9
		0000000A	00000001	3572 V10	EQU 10
		0000000B	00000001	3573 V11	EQU 11
		0000000C	00000001	3574 V12	EQU 12
		0000000D	00000001	3575 V13	EQU 13
		0000000E	00000001	3576 V14	EQU 14
		0000000F	00000001	3577 V15	EQU 15
		00000010	00000001	3578 V16	EQU 16
		00000011	00000001	3579 V17	EQU 17
		00000012	00000001	3580 V18	EQU 18
		00000013	00000001	3581 V19	EQU 19
		00000014	00000001	3582 V20	EQU 20
		00000015	00000001	3583 V21	EQU 21

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES												
					2697	2720	2721	2723	2724	2747	2748	2750	2751	2777	2778	2780	2781
					2804	2805	2807	2808	2831	2832	2834	2835	2858	2859	2861	2862	2885
					2886	2888	2889	2912	2913	2915	2916	2939	2940	2942	2943	2966	2967
					2969	2970	2997	2998	3000	3001	3024	3025	3027	3028	3051	3052	3054
					3055	3078	3079	3081	3082	3105	3106	3108	3109	3133	3134	3136	3137
					3160	3161	3163	3164	3187	3188	3190	3191	3217	3218	3220	3221	3244
					3245	3247	3248	3271	3272	3274	3275	3298	3299	3301	3302	3325	3326
					3328	3329	3353	3354	3356	3357	3380	3381	3383	3384	3407	3408	3410
					3411												
R3	U	00000003	1	3544													
R4	U	00000004	1	3545													
R5	U	00000005	1	3546	114	115	120	245	253	546	567	573	594	600	621	627	648
					654	675	684	705	711	732	738	759	765	786	792	813	823
					844	850	871	877	898	904	925	931	952	961	982	988	1009
					1015	1036	1042	1063	1069	1090	1100	1121	1127	1148	1154	1175	1181
					1202	1208	1229	1238	1259	1265	1286	1292	1313	1319	1340	1346	1367
					1377	1398	1404	1425	1431	1452	1458	1479	1485	1506	1515	1536	1542
					1563	1569	1590	1596	1617	1623	1644	1665	1686	1692	1713	1719	1740
					1746	1767	1773	1794	1800	1821	1827	1848	1854	1875	1884	1905	1911
					1932	1938	1959	1965	1986	1992	2013	2019	2040	2046	2067	2073	2094
					2104	2125	2131	2152	2158	2179	2185	2206	2212	2233	2239	2260	2266
					2287	2293	2314	2323	2344	2350	2371	2377	2398	2404	2425	2431	2452
					2458	2479	2485	2506	2512	2533	2543	2564	2570	2591	2597	2618	2624
					2645	2651	2672	2679	2700	2706	2727	2733	2754	2763	2784	2790	2811
					2817	2838	2844	2865	2871	2892	2898	2919	2925	2946	2952	2973	2983
					3004	3010	3031	3037	3058	3064	3085	3091	3112	3119	3140	3146	3167
					3173	3194	3203	3224	3230	3251	3257	3278	3284	3305	3311	3332	3339
					3360	3366	3387	3393	3414								
R6	U	00000006	1	3547													
R7	U	00000007	1	3548													
R8	U	00000008	1	3549	89	92	93	94	96								
R9	U	00000009	1	3550	90	96	97	99									
RE1	F	000011D0	4	566	556	560											
RE10	F	000014E8	4	812	802	806											
RE100	F	000033D8	4	3304	3294	3298											
RE101	F	00003430	4	3331	3321	3325											
RE102	F	00003488	4	3359	3349	3353											
RE103	F	000034E0	4	3386	3376	3380											
RE104	F	00003538	4	3413	3403	3407											
RE11	F	00001540	4	843	833	837											
RE12	F	00001598	4	870	860	864											
RE13	F	000015F0	4	897	887	891											
RE14	F	00001648	4	924	914	918											
RE15	F	000016A0	4	951	941	945											
RE16	F	000016F8	4	981	971	975											
RE17	F	00001750	4	1008	998	1002											
RE18	F	000017A8	4	1035	1025	1029											
RE19	F	00001800	4	1062	1052	1056											
RE2	F	00001228	4	593	583	587											
RE20	F	00001858	4	1089	1079	1083											
RE21	F	000018B0	4	1120	1110	1114											
RE22	F	00001908	4	1147	1137	1141											
RE23	F	00001960	4	1174	1164	1168											
RE24	F	000019B8	4	1201	1191	1195											
RE25	F	00001A10	4	1228	1218	1222											
RE26	F	00001A68	4	1258	1248	1252											

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE27	F	00001AC0	4	1285	1275 1279
RE28	F	00001B18	4	1312	1302 1306
RE29	F	00001B70	4	1339	1329 1333
RE3	F	00001280	4	620	610 614
RE30	F	00001BC8	4	1366	1356 1360
RE31	F	00001C20	4	1397	1387 1391
RE32	F	00001C78	4	1424	1414 1418
RE33	F	00001CD0	4	1451	1441 1445
RE34	F	00001D28	4	1478	1468 1472
RE35	F	00001D80	4	1505	1495 1499
RE36	F	00001DD8	4	1535	1525 1529
RE37	F	00001E30	4	1562	1552 1556
RE38	F	00001E88	4	1589	1579 1583
RE39	F	00001EE0	4	1616	1606 1610
RE4	F	000012D8	4	647	637 641
RE40	F	00001F38	4	1643	1633 1637
RE41	F	00001F90	4	1685	1675 1679
RE42	F	00001FE8	4	1712	1702 1706
RE43	F	00002040	4	1739	1729 1733
RE44	F	00002098	4	1766	1756 1760
RE45	F	000020F0	4	1793	1783 1787
RE46	F	00002148	4	1820	1810 1814
RE47	F	000021A0	4	1847	1837 1841
RE48	F	000021F8	4	1874	1864 1868
RE49	F	00002250	4	1904	1894 1898
RE5	F	00001330	4	674	664 668
RE50	F	000022A8	4	1931	1921 1925
RE51	F	00002300	4	1958	1948 1952
RE52	F	00002358	4	1985	1975 1979
RE53	F	000023B0	4	2012	2002 2006
RE54	F	00002408	4	2039	2029 2033
RE55	F	00002460	4	2066	2056 2060
RE56	F	000024B8	4	2093	2083 2087
RE57	F	00002510	4	2124	2114 2118
RE58	F	00002568	4	2151	2141 2145
RE59	F	000025C0	4	2178	2168 2172
RE6	F	00001388	4	704	694 698
RE60	F	00002618	4	2205	2195 2199
RE61	F	00002670	4	2232	2222 2226
RE62	F	000026C8	4	2259	2249 2253
RE63	F	00002720	4	2286	2276 2280
RE64	F	00002778	4	2313	2303 2307
RE65	F	000027D0	4	2343	2333 2337
RE66	F	00002828	4	2370	2360 2364
RE67	F	00002880	4	2397	2387 2391
RE68	F	000028D8	4	2424	2414 2418
RE69	F	00002930	4	2451	2441 2445
RE7	F	000013E0	4	731	721 725
RE70	F	00002988	4	2478	2468 2472
RE71	F	000029E0	4	2505	2495 2499
RE72	F	00002A38	4	2532	2522 2526
RE73	F	00002A90	4	2563	2553 2557
RE74	F	00002AE8	4	2590	2580 2584
RE75	F	00002B40	4	2617	2607 2611
RE76	F	00002B98	4	2644	2634 2638
RE77	F	00002BF0	4	2671	2661 2665

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
RE78	F	00002C48	4	2699	2689	2693
RE79	F	00002CA0	4	2726	2716	2720
RE8	F	00001438	4	758	748	752
RE80	F	00002CF8	4	2753	2743	2747
RE81	F	00002D50	4	2783	2773	2777
RE82	F	00002DA8	4	2810	2800	2804
RE83	F	00002E00	4	2837	2827	2831
RE84	F	00002E58	4	2864	2854	2858
RE85	F	00002EB0	4	2891	2881	2885
RE86	F	00002F08	4	2918	2908	2912
RE87	F	00002F60	4	2945	2935	2939
RE88	F	00002FB8	4	2972	2962	2966
RE89	F	00003010	4	3003	2993	2997
RE9	F	00001490	4	785	775	779
RE90	F	00003068	4	3030	3020	3024
RE91	F	000030C0	4	3057	3047	3051
RE92	F	00003118	4	3084	3074	3078
RE93	F	00003170	4	3111	3101	3105
RE94	F	000031C8	4	3139	3129	3133
RE95	F	00003220	4	3166	3156	3160
RE96	F	00003278	4	3193	3183	3187
RE97	F	000032D0	4	3223	3213	3217
RE98	F	00003328	4	3250	3240	3244
RE99	F	00003380	4	3277	3267	3271
REA1	A	000011A8	4	556		
REA10	A	000014C0	4	802		
REA100	A	000033B0	4	3294		
REA101	A	00003408	4	3321		
REA102	A	00003460	4	3349		
REA103	A	000034B8	4	3376		
REA104	A	00003510	4	3403		
REA11	A	00001518	4	833		
REA12	A	00001570	4	860		
REA13	A	000015C8	4	887		
REA14	A	00001620	4	914		
REA15	A	00001678	4	941		
REA16	A	000016D0	4	971		
REA17	A	00001728	4	998		
REA18	A	00001780	4	1025		
REA19	A	000017D8	4	1052		
REA2	A	00001200	4	583		
REA20	A	00001830	4	1079		
REA21	A	00001888	4	1110		
REA22	A	000018E0	4	1137		
REA23	A	00001938	4	1164		
REA24	A	00001990	4	1191		
REA25	A	000019E8	4	1218		
REA26	A	00001A40	4	1248		
REA27	A	00001A98	4	1275		
REA28	A	00001AF0	4	1302		
REA29	A	00001B48	4	1329		
REA3	A	00001258	4	610		
REA30	A	00001BA0	4	1356		
REA31	A	00001BF8	4	1387		
REA32	A	00001C50	4	1414		
REA33	A	00001CA8	4	1441		

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA34	A	00001D00	4	1468	
REA35	A	00001D58	4	1495	
REA36	A	00001DB0	4	1525	
REA37	A	00001E08	4	1552	
REA38	A	00001E60	4	1579	
REA39	A	00001EB8	4	1606	
REA4	A	000012B0	4	637	
REA40	A	00001F10	4	1633	
REA41	A	00001F68	4	1675	
REA42	A	00001FC0	4	1702	
REA43	A	00002018	4	1729	
REA44	A	00002070	4	1756	
REA45	A	000020C8	4	1783	
REA46	A	00002120	4	1810	
REA47	A	00002178	4	1837	
REA48	A	000021D0	4	1864	
REA49	A	00002228	4	1894	
REA5	A	00001308	4	664	
REA50	A	00002280	4	1921	
REA51	A	000022D8	4	1948	
REA52	A	00002330	4	1975	
REA53	A	00002388	4	2002	
REA54	A	000023E0	4	2029	
REA55	A	00002438	4	2056	
REA56	A	00002490	4	2083	
REA57	A	000024E8	4	2114	
REA58	A	00002540	4	2141	
REA59	A	00002598	4	2168	
REA6	A	00001360	4	694	
REA60	A	000025F0	4	2195	
REA61	A	00002648	4	2222	
REA62	A	000026A0	4	2249	
REA63	A	000026F8	4	2276	
REA64	A	00002750	4	2303	
REA65	A	000027A8	4	2333	
REA66	A	00002800	4	2360	
REA67	A	00002858	4	2387	
REA68	A	000028B0	4	2414	
REA69	A	00002908	4	2441	
REA7	A	000013B8	4	721	
REA70	A	00002960	4	2468	
REA71	A	000029B8	4	2495	
REA72	A	00002A10	4	2522	
REA73	A	00002A68	4	2553	
REA74	A	00002AC0	4	2580	
REA75	A	00002B18	4	2607	
REA76	A	00002B70	4	2634	
REA77	A	00002BC8	4	2661	
REA78	A	00002C20	4	2689	
REA79	A	00002C78	4	2716	
REA8	A	00001410	4	748	
REA80	A	00002CD0	4	2743	
REA81	A	00002D28	4	2773	
REA82	A	00002D80	4	2800	
REA83	A	00002DD8	4	2827	
REA84	A	00002E30	4	2854	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES		
REA85	A	00002E88	4	2881			
REA86	A	00002EE0	4	2908			
REA87	A	00002F38	4	2935			
REA88	A	00002F90	4	2962			
REA89	A	00002FE8	4	2993			
REA9	A	00001468	4	775			
REA90	A	00003040	4	3020			
REA91	A	00003098	4	3047			
REA92	A	000030F0	4	3074			
REA93	A	00003148	4	3101			
REA94	A	000031A0	4	3129			
REA95	A	000031F8	4	3156			
REA96	A	00003250	4	3183			
REA97	A	000032A8	4	3213			
REA98	A	00003300	4	3240			
REA99	A	00003358	4	3267			
READDR	A	00000018	4	428	130		
REG2LOW	U	000000DD	1	333			
REG2PATT	U	AABBCCDD	1	332			
RELEN	A	00000014	4	427			
RPTDWSAV	D	000003A8	8	260	249	251	
RPTERROR	I	0000037E	4	244	182	216	
RPTSAVE	F	0000039C	4	257	244	254	
RPTSVR5	F	000003A0	4	258	245	253	
SVOLDPSW	U	00000140	0	54			
T1	A	00001190	4	547	3426		
T10	A	000014A8	4	793	3435		
T100	A	00003398	4	3285	3525		
T101	A	000033F0	4	3312	3526		
T102	A	00003448	4	3340	3527		
T103	A	000034A0	4	3367	3528		
T104	A	000034F8	4	3394	3529		
T11	A	00001500	4	824	3436		
T12	A	00001558	4	851	3437		
T13	A	000015B0	4	878	3438		
T14	A	00001608	4	905	3439		
T15	A	00001660	4	932	3440		
T16	A	000016B8	4	962	3441		
T17	A	00001710	4	989	3442		
T18	A	00001768	4	1016	3443		
T19	A	000017C0	4	1043	3444		
T2	A	000011E8	4	574	3427		
T20	A	00001818	4	1070	3445		
T21	A	00001870	4	1101	3446		
T22	A	000018C8	4	1128	3447		
T23	A	00001920	4	1155	3448		
T24	A	00001978	4	1182	3449		
T25	A	000019D0	4	1209	3450		
T26	A	00001A28	4	1239	3451		
T27	A	00001A80	4	1266	3452		
T28	A	00001AD8	4	1293	3453		
T29	A	00001B30	4	1320	3454		
T3	A	00001240	4	601	3428		
T30	A	00001B88	4	1347	3455		
T31	A	00001BE0	4	1378	3456		
T32	A	00001C38	4	1405	3457		

ASMA Ver. 0.7.0 zvector-e6-13-converttodecimal (Zvector E6 VRI-i)					02 Jun 2024 16:00:20 Page 80	
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
T33	A	00001C90	4	1432	3458	
T34	A	00001CE8	4	1459	3459	
T35	A	00001D40	4	1486	3460	
T36	A	00001D98	4	1516	3461	
T37	A	00001DF0	4	1543	3462	
T38	A	00001E48	4	1570	3463	
T39	A	00001EA0	4	1597	3464	
T4	A	00001298	4	628	3429	
T40	A	00001EF8	4	1624	3465	
T41	A	00001F50	4	1666	3466	
T42	A	00001FA8	4	1693	3467	
T43	A	00002000	4	1720	3468	
T44	A	00002058	4	1747	3469	
T45	A	000020B0	4	1774	3470	
T46	A	00002108	4	1801	3471	
T47	A	00002160	4	1828	3472	
T48	A	000021B8	4	1855	3473	
T49	A	00002210	4	1885	3474	
T5	A	000012F0	4	655	3430	
T50	A	00002268	4	1912	3475	
T51	A	000022C0	4	1939	3476	
T52	A	00002318	4	1966	3477	
T53	A	00002370	4	1993	3478	
T54	A	000023C8	4	2020	3479	
T55	A	00002420	4	2047	3480	
T56	A	00002478	4	2074	3481	
T57	A	000024D0	4	2105	3482	
T58	A	00002528	4	2132	3483	
T59	A	00002580	4	2159	3484	
T6	A	00001348	4	685	3431	
T60	A	000025D8	4	2186	3485	
T61	A	00002630	4	2213	3486	
T62	A	00002688	4	2240	3487	
T63	A	000026E0	4	2267	3488	
T64	A	00002738	4	2294	3489	
T65	A	00002790	4	2324	3490	
T66	A	000027E8	4	2351	3491	
T67	A	00002840	4	2378	3492	
T68	A	00002898	4	2405	3493	
T69	A	000028F0	4	2432	3494	
T7	A	000013A0	4	712	3432	
T70	A	00002948	4	2459	3495	
T71	A	000029A0	4	2486	3496	
T72	A	000029F8	4	2513	3497	
T73	A	00002A50	4	2544	3498	
T74	A	00002AA8	4	2571	3499	
T75	A	00002B00	4	2598	3500	
T76	A	00002B58	4	2625	3501	
T77	A	00002BB0	4	2652	3502	
T78	A	00002C08	4	2680	3503	
T79	A	00002C60	4	2707	3504	
T8	A	000013F8	4	739	3433	
T80	A	00002CB8	4	2734	3505	
T81	A	00002D10	4	2764	3506	
T82	A	00002D68	4	2791	3507	
T83	A	00002DC0	4	2818	3508	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X2	F	00001204	4	585	574
X20	F	00001834	4	1081	1070
X21	F	0000188C	4	1112	1101
X22	F	000018E4	4	1139	1128
X23	F	0000193C	4	1166	1155
X24	F	00001994	4	1193	1182
X25	F	000019EC	4	1220	1209
X26	F	00001A44	4	1250	1239
X27	F	00001A9C	4	1277	1266
X28	F	00001AF4	4	1304	1293
X29	F	00001B4C	4	1331	1320
X3	F	0000125C	4	612	601
X30	F	00001BA4	4	1358	1347
X31	F	00001BFC	4	1389	1378
X32	F	00001C54	4	1416	1405
X33	F	00001CAC	4	1443	1432
X34	F	00001D04	4	1470	1459
X35	F	00001D5C	4	1497	1486
X36	F	00001DB4	4	1527	1516
X37	F	00001E0C	4	1554	1543
X38	F	00001E64	4	1581	1570
X39	F	00001EBC	4	1608	1597
X4	F	000012B4	4	639	628
X40	F	00001F14	4	1635	1624
X41	F	00001F6C	4	1677	1666
X42	F	00001FC4	4	1704	1693
X43	F	0000201C	4	1731	1720
X44	F	00002074	4	1758	1747
X45	F	000020CC	4	1785	1774
X46	F	00002124	4	1812	1801
X47	F	0000217C	4	1839	1828
X48	F	000021D4	4	1866	1855
X49	F	0000222C	4	1896	1885
X5	F	0000130C	4	666	655
X50	F	00002284	4	1923	1912
X51	F	000022DC	4	1950	1939
X52	F	00002334	4	1977	1966
X53	F	0000238C	4	2004	1993
X54	F	000023E4	4	2031	2020
X55	F	0000243C	4	2058	2047
X56	F	00002494	4	2085	2074
X57	F	000024EC	4	2116	2105
X58	F	00002544	4	2143	2132
X59	F	0000259C	4	2170	2159
X6	F	00001364	4	696	685
X60	F	000025F4	4	2197	2186
X61	F	0000264C	4	2224	2213
X62	F	000026A4	4	2251	2240
X63	F	000026FC	4	2278	2267
X64	F	00002754	4	2305	2294
X65	F	000027AC	4	2335	2324
X66	F	00002804	4	2362	2351
X67	F	0000285C	4	2389	2378
X68	F	000028B4	4	2416	2405
X69	F	0000290C	4	2443	2432
X7	F	000013BC	4	723	712

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	14088	0000- 3707	0000- 3707
Regi on		14088	0000- 3707	0000- 3707
CSECT	ZVE6TST	14088	0000- 3707	0000- 3707

STMT	FILE NAME
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1	/devstor/dev/tests/zvector-e6-13-converttodecimal.asm
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** NO ERRORS FOUND **